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# EEE6212 Lecture 21

## “Photodetectors”

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# Outline

- Principle of light detection by semiconductors
- Photoconductor
- Photo-Diode
- Avalanche Photo-Diode
- Photo-transistor
- Charge-Coupled Device (CCD) vs. Complimentary Metal-Oxide-Semiconductor (CMOS) detector



# Detection of Light by Semiconductors

General principle – generate an electron-hole pair via an energy transition

In most cases use an **intrinsic semiconductor**

Generation of **Electron-Hole pairs by band-to-band transition** if photon energy is at least as large as the band gap

$$\frac{hc}{\lambda} = E_{\gamma} \geq E_g = eV$$

**Conduction band**

**Valence band**

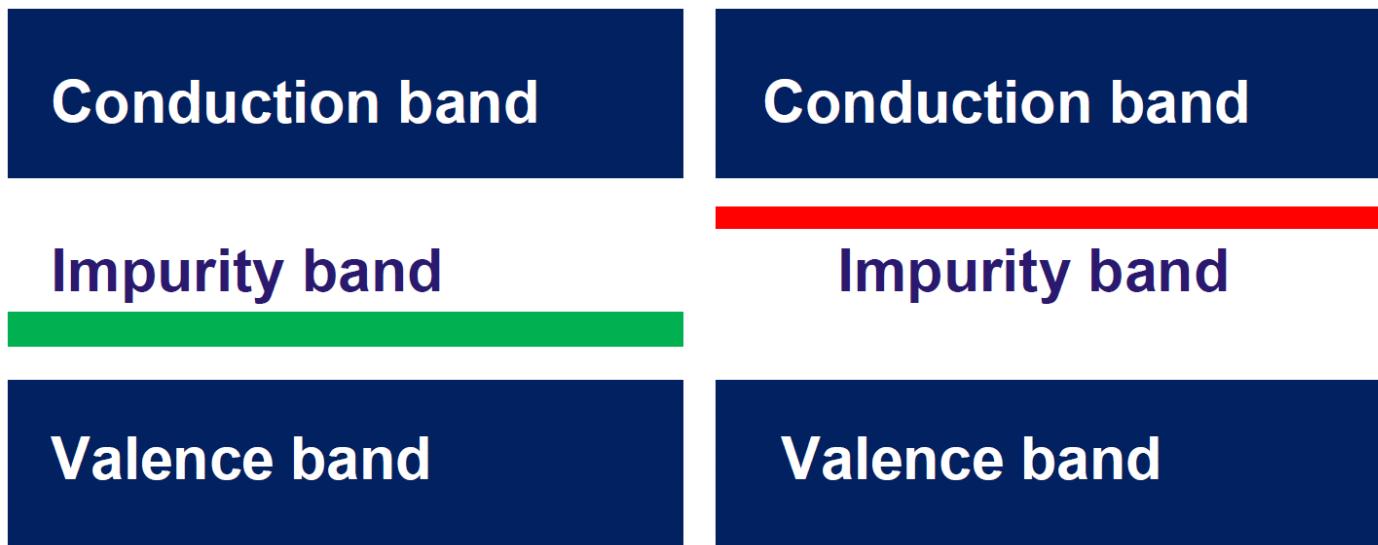


# Detection of Light by Semiconductors

For Infra-Red applications (smaller energies) also extrinsic semiconductors are used: Electron-Hole pair generation from impurity band to band edge (electron from valence to acceptor level or from donor level to conduction band)

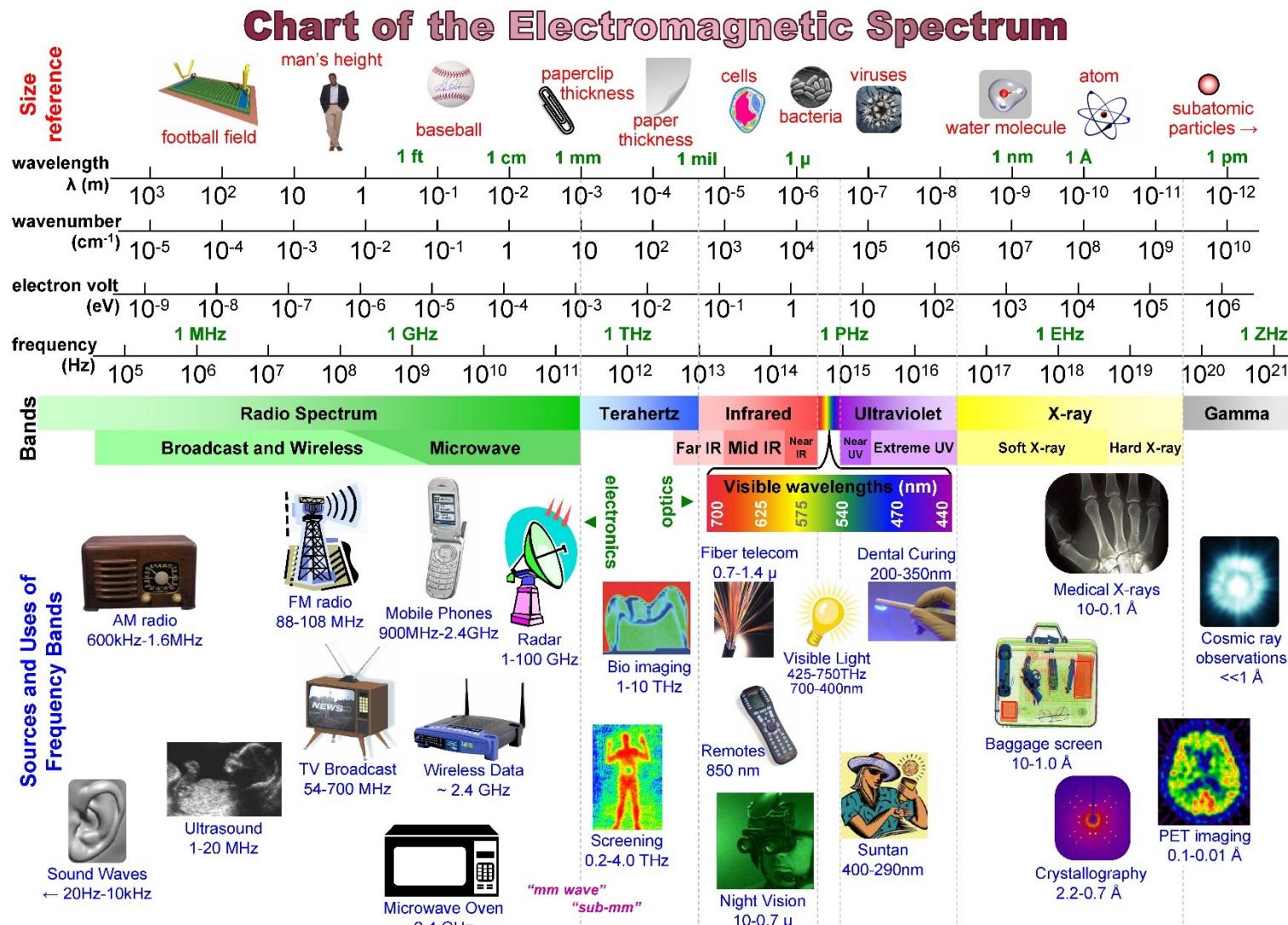
$$E_\gamma \geq E_A - E_V \text{ or } E_\gamma \geq E_C - E_D$$

Semiconductors do not “see” colours hence we need to modify our device in some way to make it wavelength specific





# The Electromagnetic Spectrum





# Spectrum and Absorption Windows

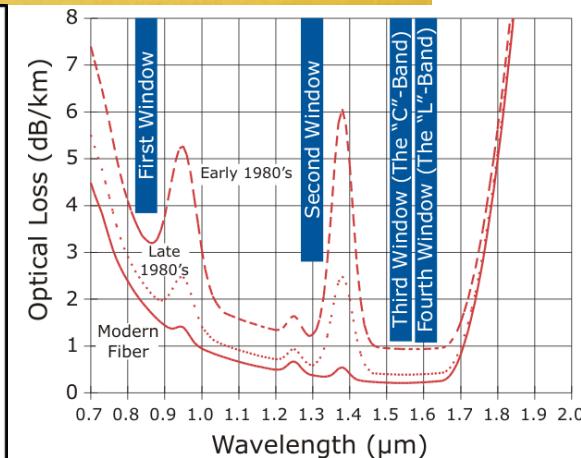
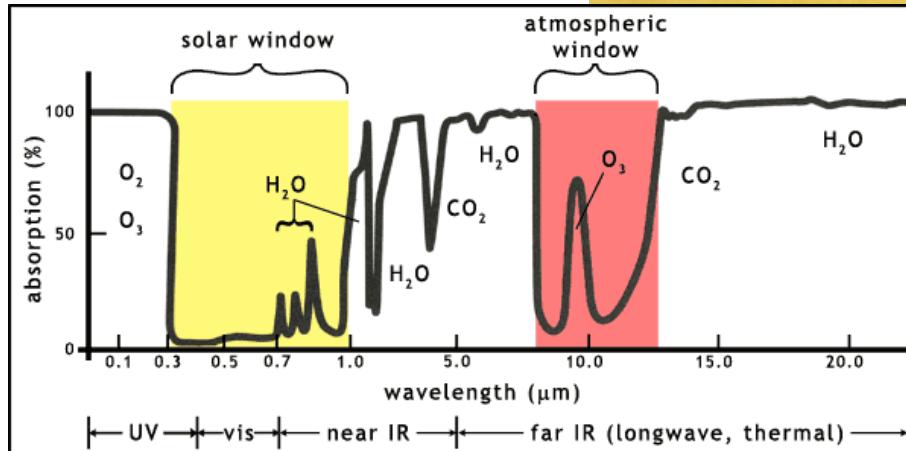
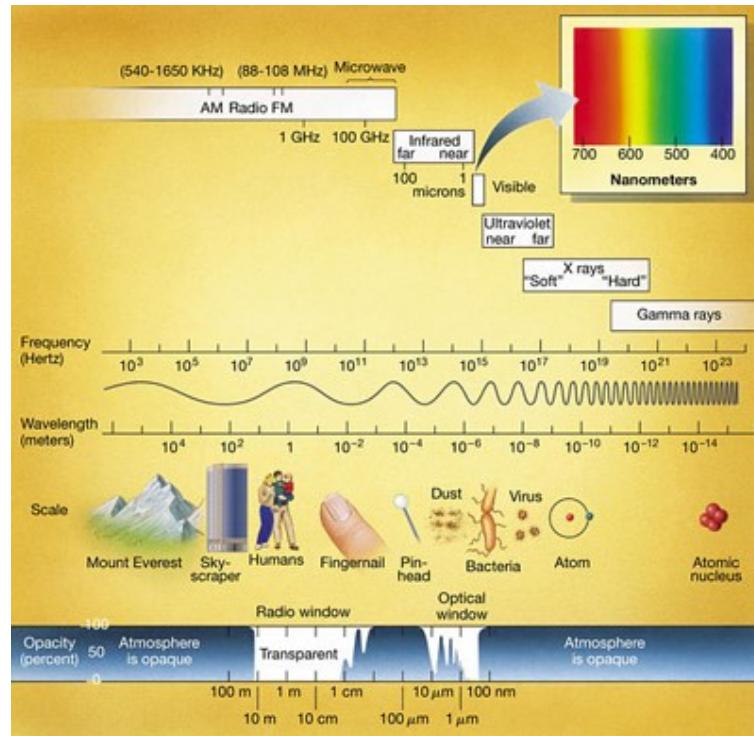
## Semiconductors

$$E_g \approx 0.6 \rightarrow 6.0 \text{ eV} = hf$$

$$f = 1.45 \times (10^{14} \rightarrow 10^{15}) \text{ Hz}$$

$$\lambda = \frac{c}{f} = 0.2 \rightarrow 2 \mu\text{m}$$

Covers the range from UV-vis-NIR





# Detector bands

## Common wavelength bands for detectors

Band 1 UV-vis-NIR	$0.19 - 1.0\mu m$	Reflected sunlight
Band 2 Short wave IR (SWIR)	$1.0 - 2.6\mu m$	Some reflected sunlight and some emitted radiation
Band 3 Mid wave IR (MWIR)	$3 - 5\mu m$	Emitted thermal radiation
Band 4 Long wave IR (LWIR)	$8 - 14\mu m$	
Band 5 Far IR (FIR)	$> 15\mu m$	

Common wavelength windows for telecommunications are centred around the H<sub>2</sub>O absorption minima of the red/IR spectrum

1 <sup>st</sup> window	red	800-900nm	Si, GaAs
2 <sup>nd</sup> window	SWIR I	~1300nm	InGaAs, Ge
3 <sup>rd</sup> window	SWIR II	~1550nm	InGaAs, Ge, HgCdTe



# Types of detector

## Photo-conductor (PC)

Doped semiconductor with metal contacts

Cheap

## Photo-Diode (PD)

p-i-n diode with metal contacts

unity gain (1), high quantum efficiency, fast ( $10^{-9} \rightarrow 10^{-11}s$ )

## Avalanche Photo-Diode (APD)

Diode operated near reverse breakdown voltage

High gain ( $10^2 \rightarrow 10^4$ ), fast ( $10^{-10}s$ ), potentially noisy

For a detailed description see [EE337 Lecture 4](#)

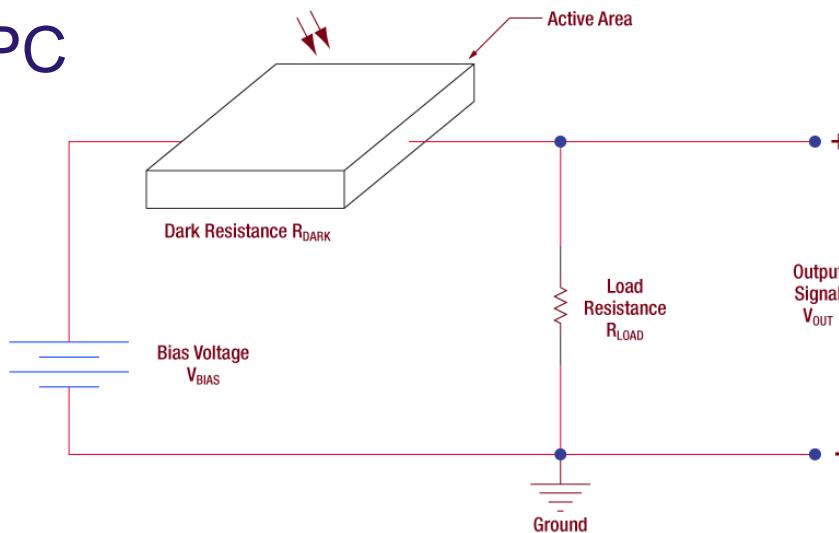
## Photo-Transistor (PT)

Medium high gain ( $10^2 \rightarrow 10^3$ ), slower ( $10^{-6}s$ )

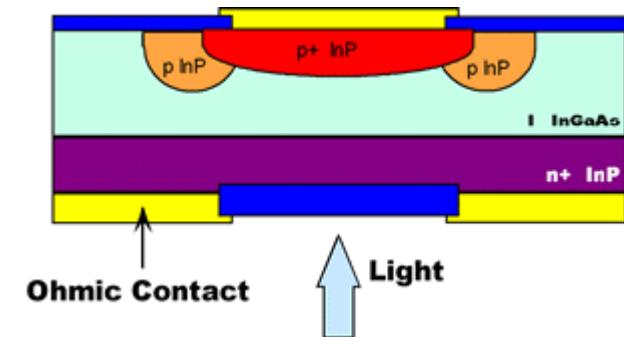


# Types of detector

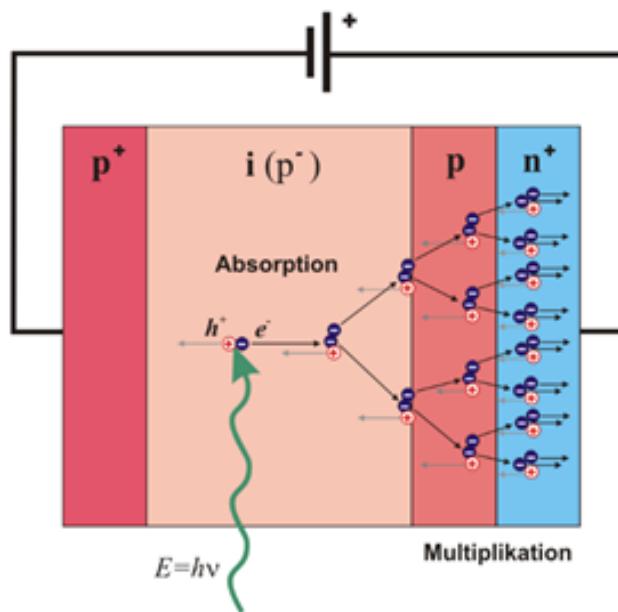
PC



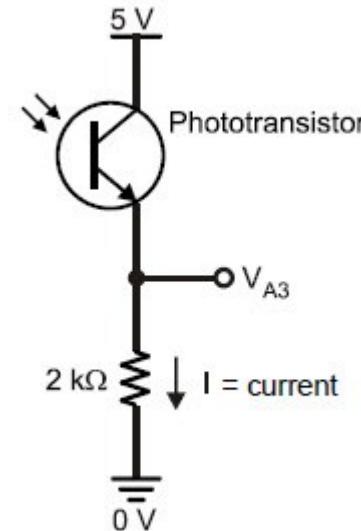
PD



APD



PT



[http://www.thorlabs.de/newgroupage9.cfm?objectgroup\\_id=9020](http://www.thorlabs.de/newgroupage9.cfm?objectgroup_id=9020)  
[http://www.olson-technology.com/mr\\_fiber/glossary-pq.htm#Photodiode](http://www.olson-technology.com/mr_fiber/glossary-pq.htm#Photodiode)

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<http://learn.parallax.com/tutorials/robot/shield-bot/robotics-board-education-shield-arduino/chapter-6-light-sensitive-il>



# Quantum Efficiency

Definition of (external) quantum efficiency ( $\text{EQE} = \eta$ )

Number of electron-hole pairs generated per incident photon

$$\eta = \frac{\left(\frac{I_{photo}}{e}\right)}{\left(\frac{P_{opt}}{hf}\right)} = \frac{I_{photo} \times hf}{e \times P_{opt}}$$

Where,  $I_{photo}$  is the measure photocurrent,  $P_{opt}$  the incident optical power and the photon energy is  $hf$

To maximise efficiency, carrier loss due to recombination within the semiconductor must be minimised. This is achieved in a p-i-n diode by confining illumination and absorption to the depleted i-region, and by separating this from the carrier multiplication region (in APDs)

Carrier loss through recombination must be minimised by surface passivation, wide band gap p and n layers can be used to reduce the “dark current”



# Photon absorption and QE

When light falls on a semiconductor its intensity falls exponentially with depth

$$I(z) = I_0 e^{-\alpha z}$$

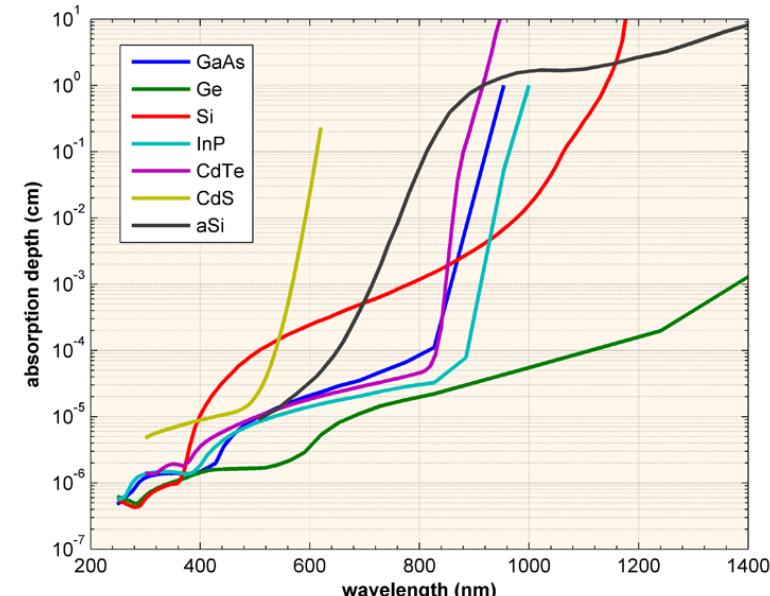
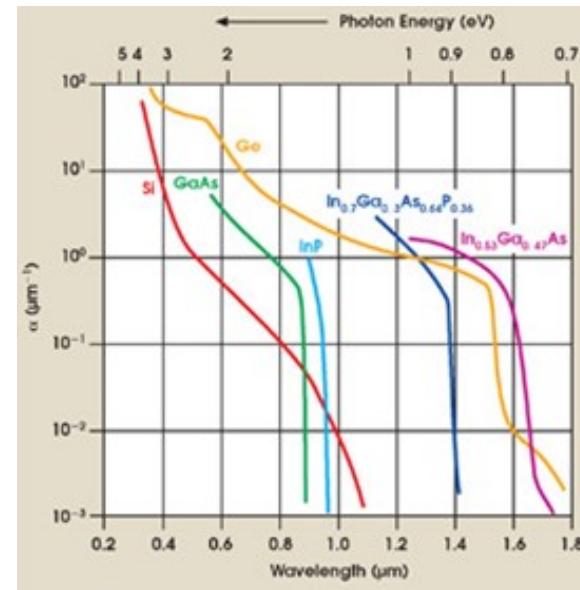
With an **absorption coefficient**

$$\alpha = 2\kappa k = \frac{4\pi\kappa}{\lambda} \sim 10^6 \rightarrow 10^8 m^{-1}$$

above the band edge

Within the depletion region of area  $A$  and total depth  $d$  for a reflectivity  $R$  at the semiconductor surface the generation rate for electron-hole pairs is

$$g(z) = (1 - R) \left( \frac{P_{opt}}{A h f} \right) e^{-\alpha z}$$





# Photon absorption and QE

Assuming light is absorbed in the intrinsic region only, the generated photocurrent in the depletion region is

$$\begin{aligned} I_{photo} &= eA \int_0^d g(z) dz \\ &= e(1 - R) \left( \frac{P_{opt}}{hf} \right) \int_0^d e^{-\alpha z} dz \\ &= e(1 - R) \left( \frac{P_{opt}}{hf} \right) [1 - e^{-\alpha d}] \end{aligned}$$

Insert this into the expression for the quantum efficiency

$$\begin{aligned} \eta &= \left( \frac{I_{photo}}{e} \right) \times \left( \frac{hf}{P_{opt}} \right) \\ \eta &= (1 - R)[1 - e^{-\alpha d}] \end{aligned}$$



# Photon absorption and QE

$$\eta = (1 - R)[1 - e^{-\alpha d}]$$

This shows that

Reflection at the interface to air must be minimised ( $R \rightarrow 0$ )

Need for anti reflective coatings and “window” layers

The depth of the depletion region  $d$  must be made large

However the latter can be costly for epitaxy

so typically  $d \sim 1/\alpha \sim \text{several } \mu\text{m}$  is chosen

Further increases would reduce the response speed, given by the time it takes the carriers to transit the depletion region

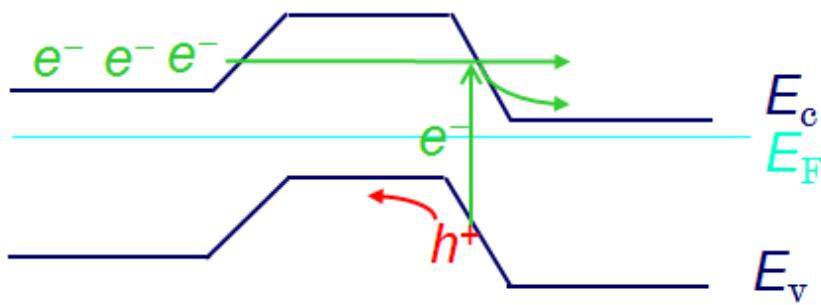
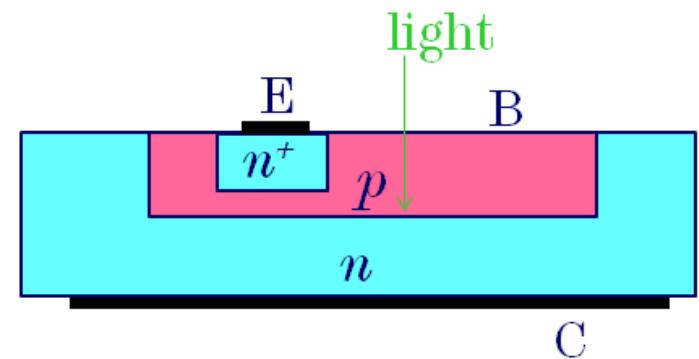
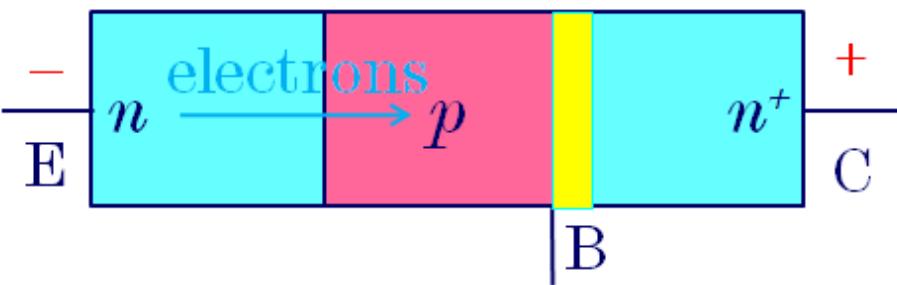
(which is  $\propto 1/d$ )



# Photo-transistor

Principle fabrication steps for a lateral BJT

- 1) n-type substrate for npn [p type substrate for pnp]
- 2) Create base region by p [n] doping a wider region several  $\mu m$  deep
- 3) Form emitter by n+ [p+] doping a small part of that sub region
- 4) Deposit metal contacts for E and C (for B not necessary)



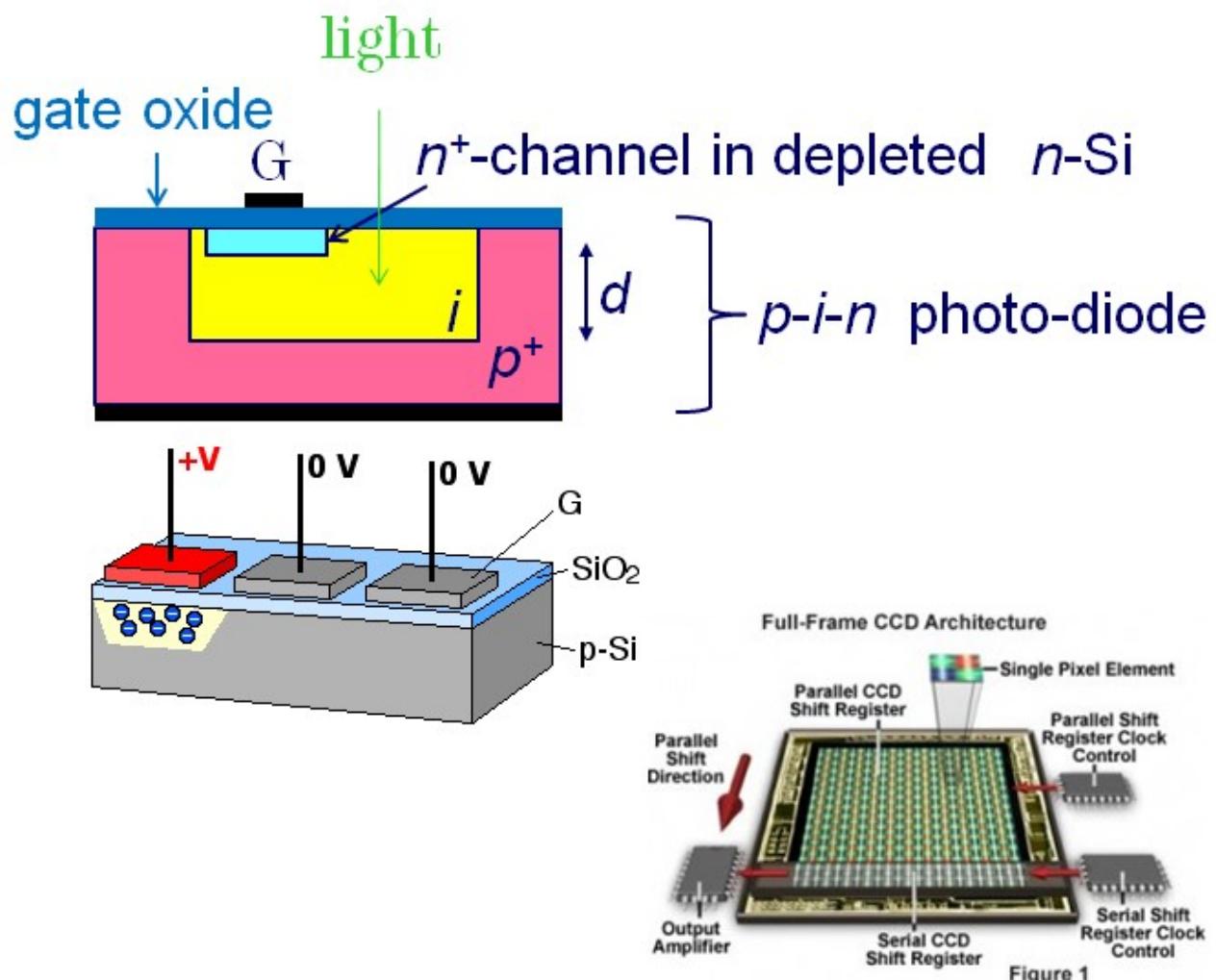
holes ( $h^+$ ) generated predominantly at the lower part of the base accumulate in the base. Electrons ( $e^-$ ) can move to the collector. If they reach it, a high photo current can flow from E to C, due to carrier injection at E, giving  $gain >> 1$ .



# Charge-Coupled Devices (CCDs)

Principle: Up to  $10^5$  electrons accumulate in n-type channel under gate on top of photo-diode and are read out serially by charge transfer along the surface from one pixel/row to the next ("shift register")

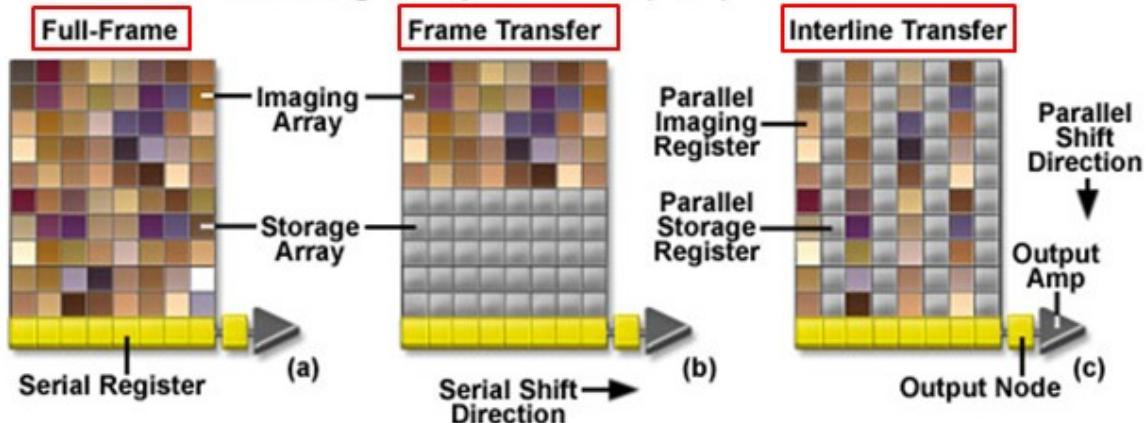
The last capacitor in the array dumps its charge into an op-amp. As charge collected is proportional to light intensity the response is **linear over a large range**, the quantum efficiency can be very high, commonly  $\eta = 0.7 \rightarrow 0.95$



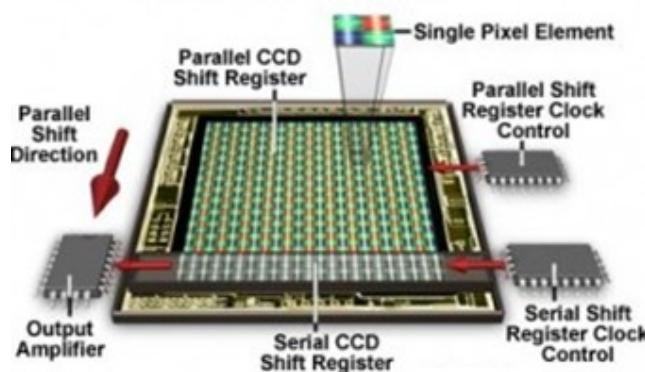


# CCD architectures

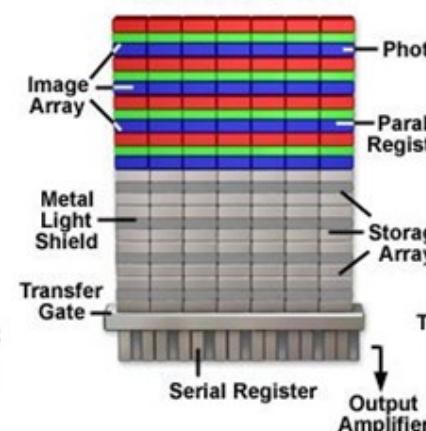
Common Charge-Coupled Device (CCD) Architectures



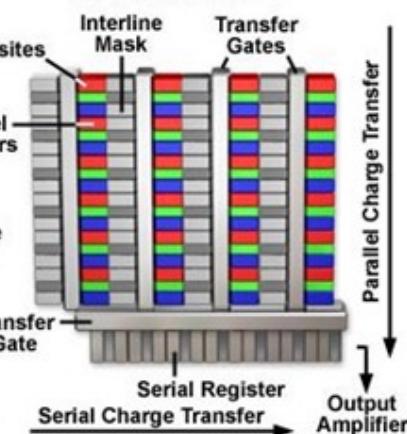
Full-Frame CCD Architecture



Frame Transfer CCD



Interline Transfer CCD



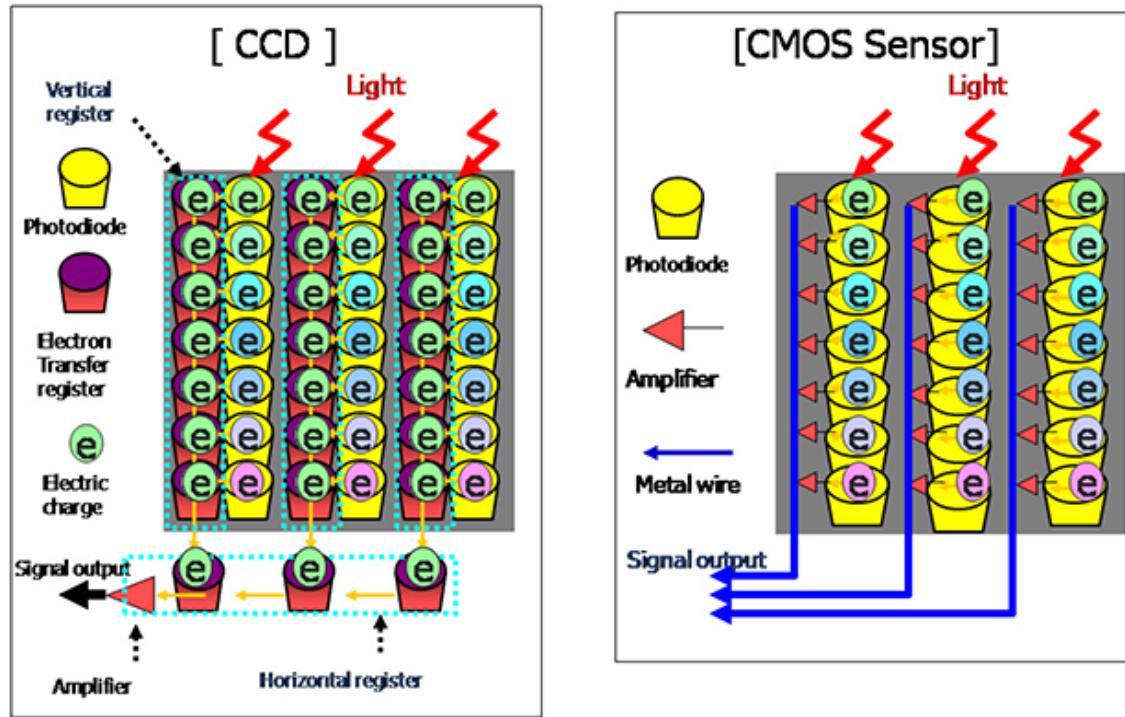
charge transfer method from one pixel to next, line-by-line, column-by column  
shutter mechanical (slow)

into separate storage array electronic

into neighbouring column mechanical (fast)



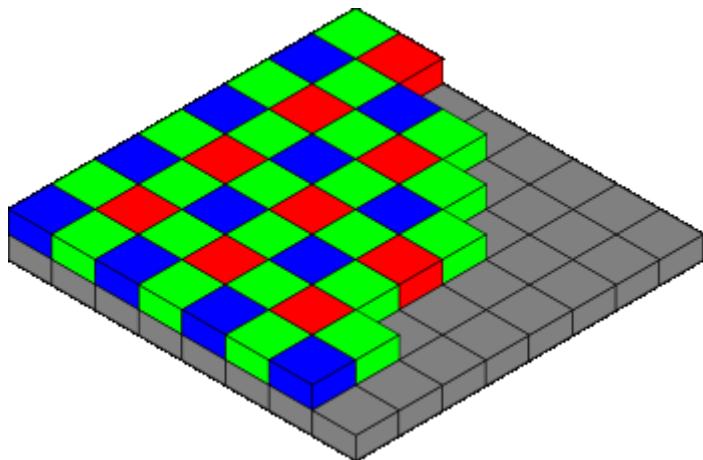
# CCD vs CMOS detectors



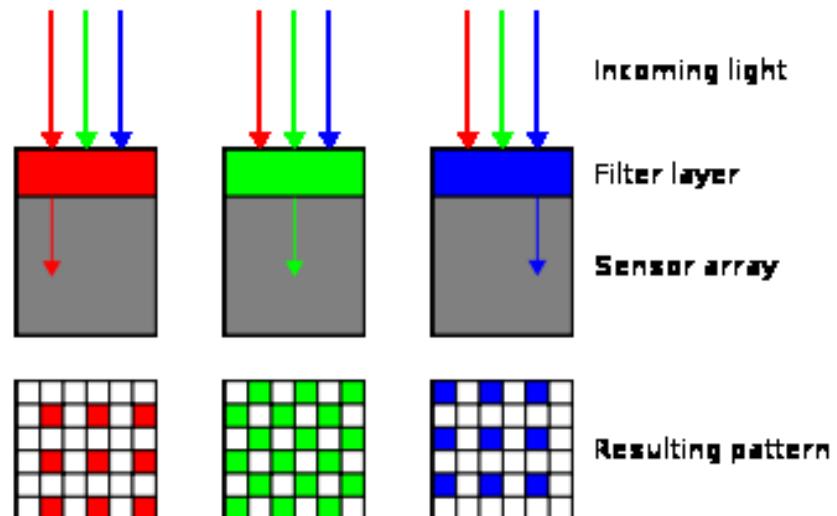
Pixel	photodiode with capacitor
Read out	successive by shift register
Speed	<b>slow</b>
Price	<b>expensive</b>
Signal cross talk	<b>vertical smear ("blooming")</b>
Noise level	<b>low</b>
	photodiode with transistor
	direct for each pixel
	<b>fast</b>
	<b>cheap (since late 90s)</b>
	<b>weak blooming</b>
	<b>higher</b>



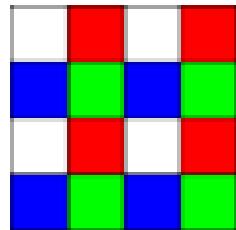
# Colour Filters for 2D detectors



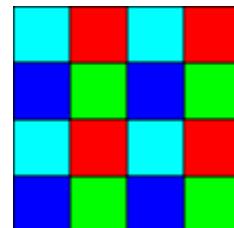
standard Bayer filter (G-RGB),  
needs additional anti-moiré filter



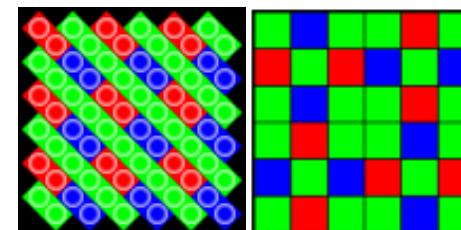
other colour filter schemes



RGB-W filter by Kodak



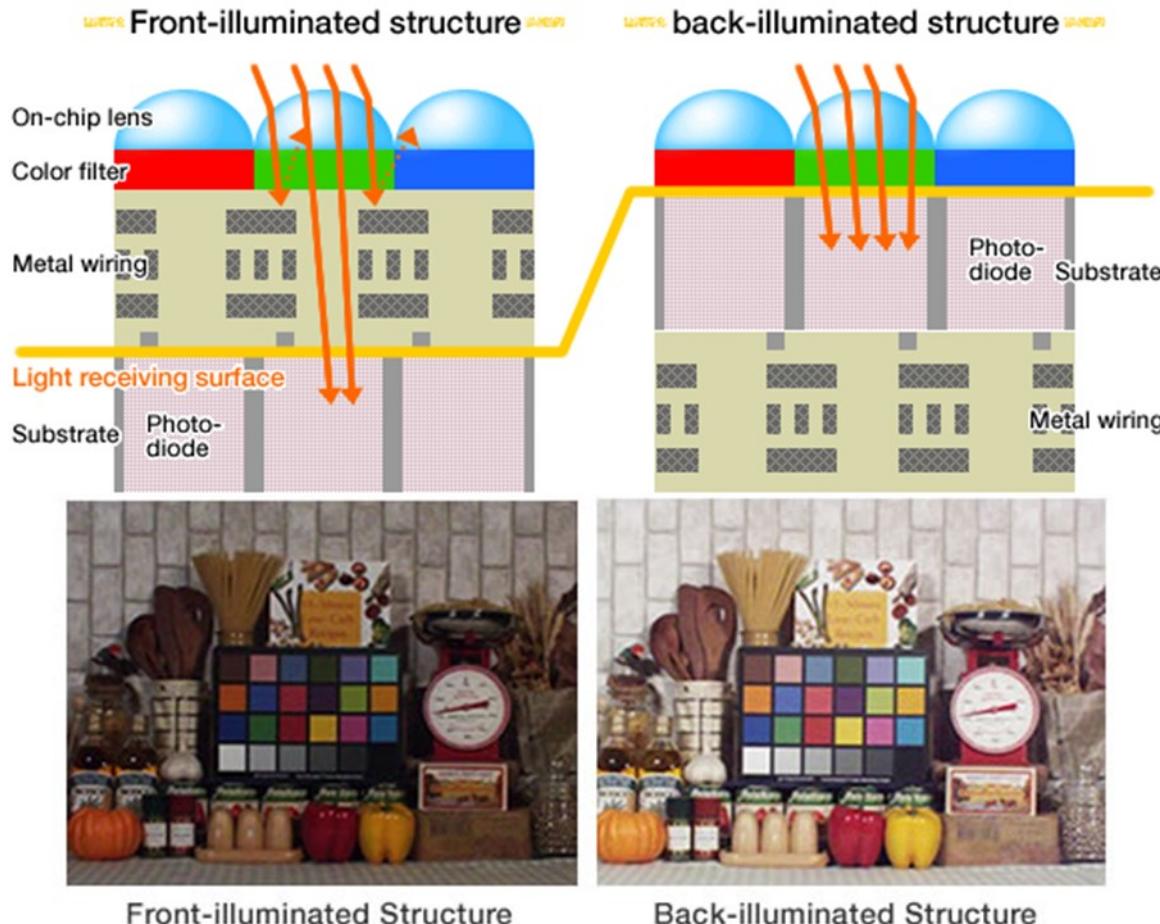
RGB-E filter by Sony



EXR and X-Trans filter by Fuji



# Front vs back-illumination



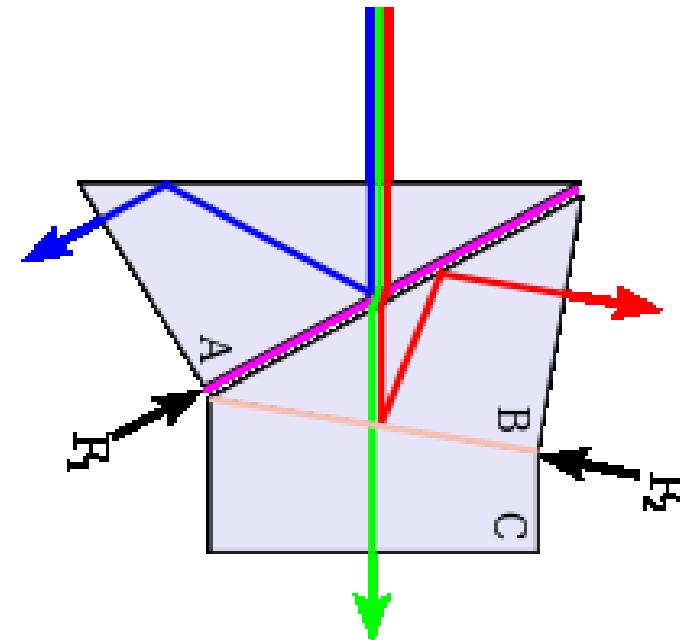
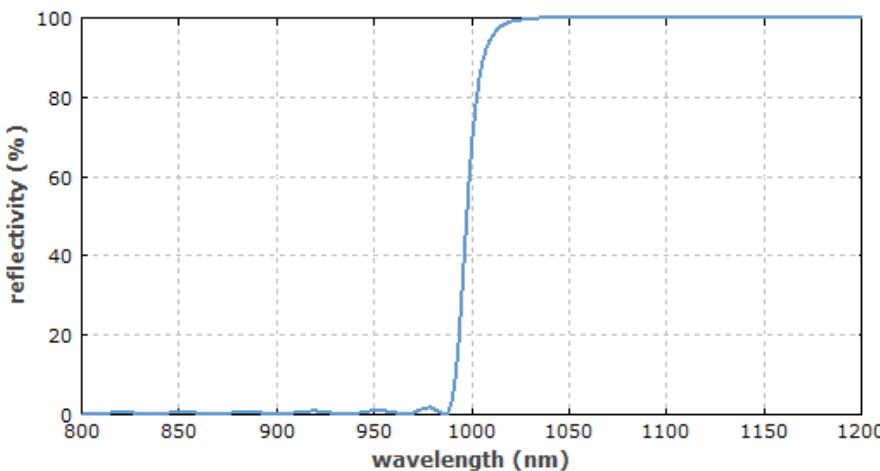
Flipping the processed wafer over places the photo-diodes directly under the colour filter.

More light reaches them, giving more intensity and less noise.

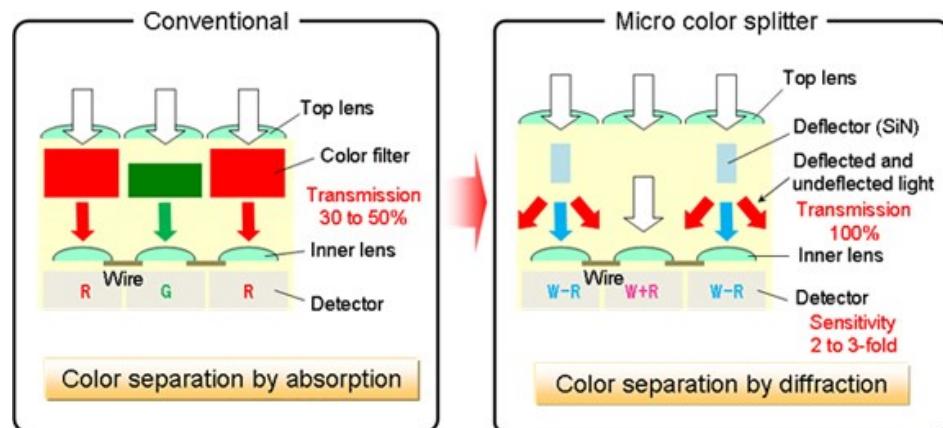


# Alternative approaches for colour (I)

Double dichroic (trichroic) colour separation by double prisms used as beam splitters

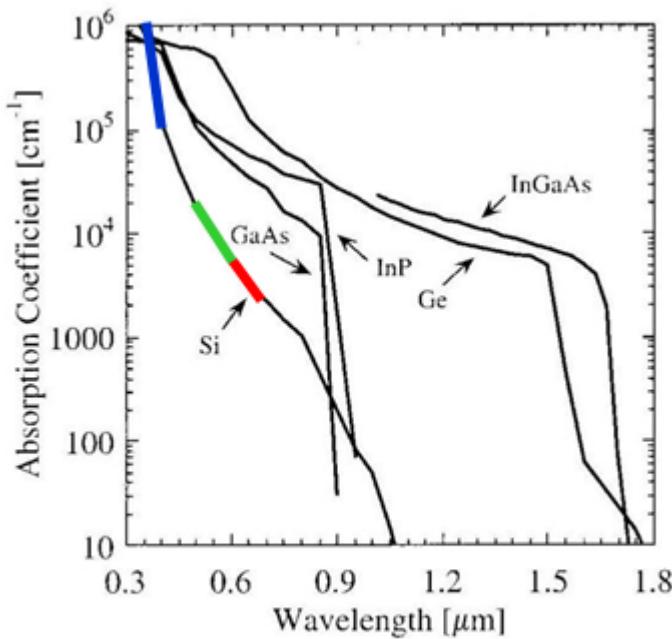


Colour separation by diffraction grating as a deflector whose angular separate is proportional to the wavelength

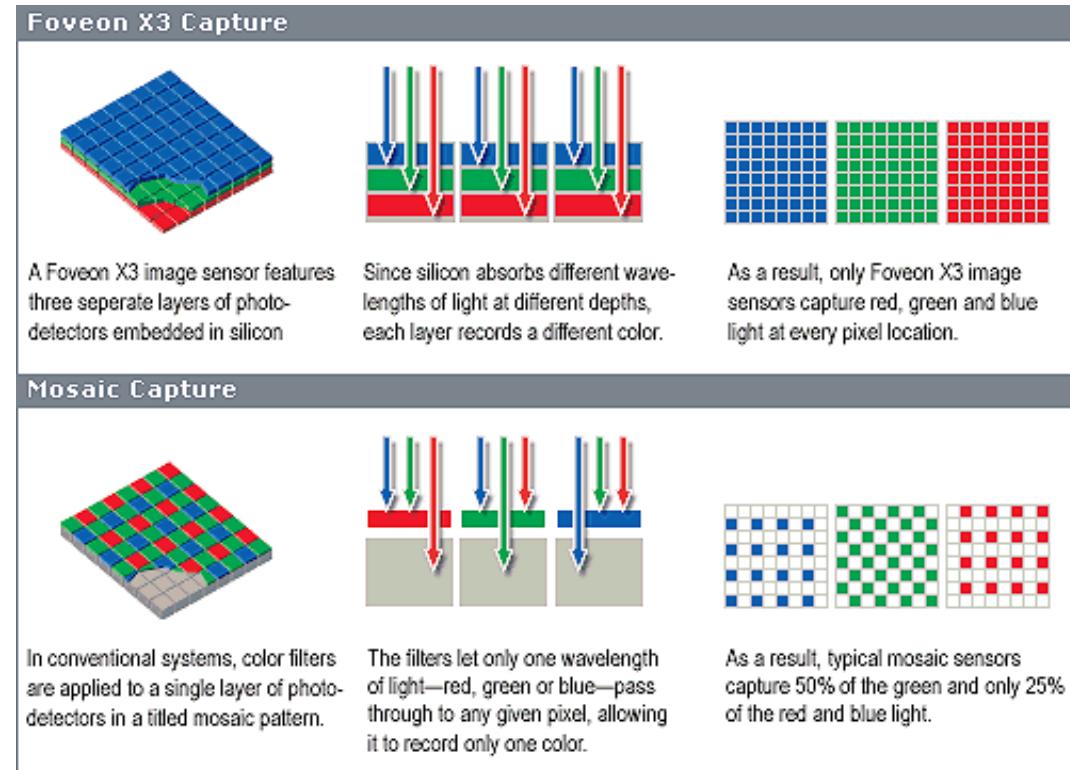




# Alternative approaches for colour (II)



Handbook of Optical Constants of Solids, edited by Edward D. Palik, (1985), Academic Press NY.



Optimisation of depth dependent absorption in 3 individual layers of CMOS sensors stacked on top of each other



# Summary

- Principle of light detection by semiconductors
- Photoconductor
- Photo-Diode
- Avalanche Photo-Diode
- Photo-transistor
- Charge-Coupled Device (CCD) vs. Complimentary Metal-Oxide-Semiconductor (CMOS) detector



# What have we not discussed?

Quantum Photodetectors...

Using the wavelength specific nature of the energy transitions of Quantum Wells, Wires or Dots to tune the absorption to regions of interest

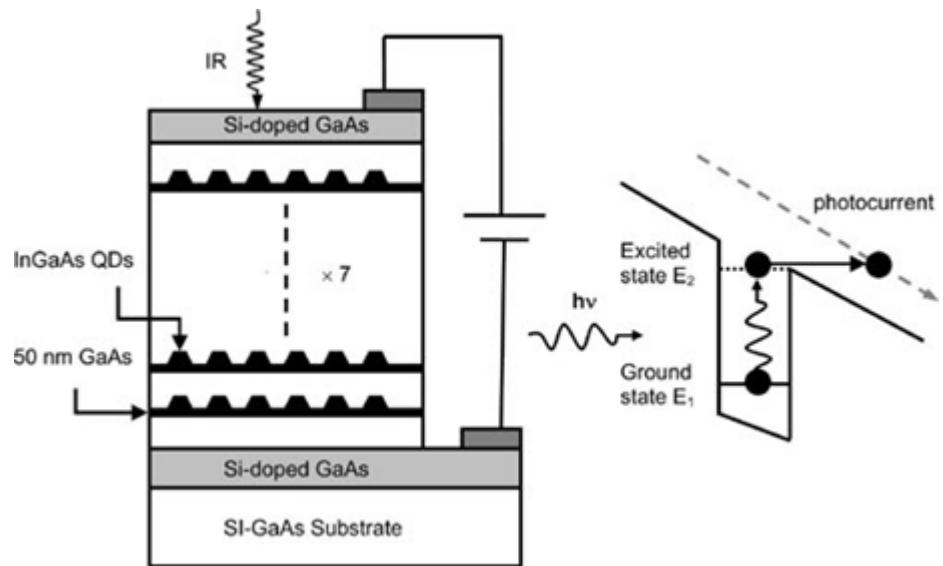
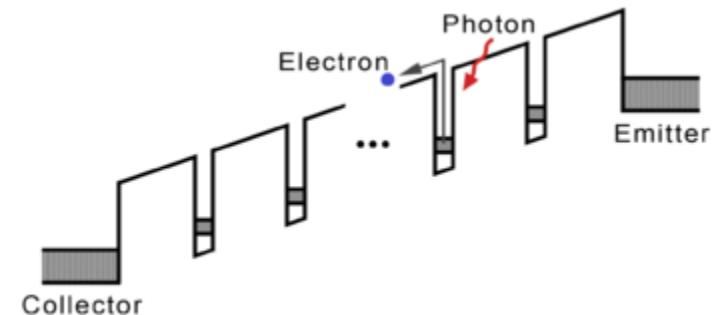
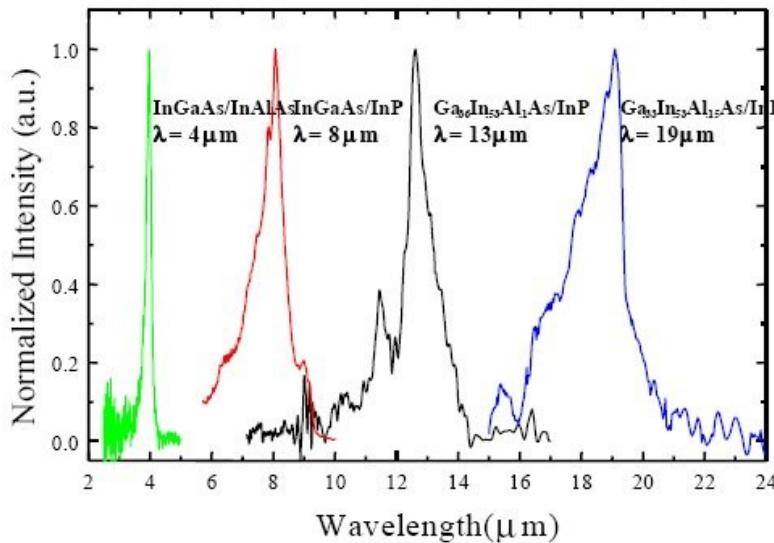
Quantum Well Infra-Red Photodetector (QWIP)

Quantum Dot Infra-Red Photodetector (QDIP)

Quantum Cascade Photodetector (QCD)

Operating temperature of detectors

Eg. Cooling a detector to reduce noise and/or dark currents etc.





# “The practical.....”

## Wednesday's lecture

“If you wont come to see me, I'll come to see you!”

On Wednesday I'll go over the general ideas behind the practical and give an example of the XRD + PL fitting approach as suggested in all the material you have been given so far (Lecture 11 notes, practical handouts, growth sheets, two sets of “next steps”, “software” slides etc.)

I will **not** do it all for you but can only try to help!



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# EEE6212 Lecture 22

## “Nanotechnology...”

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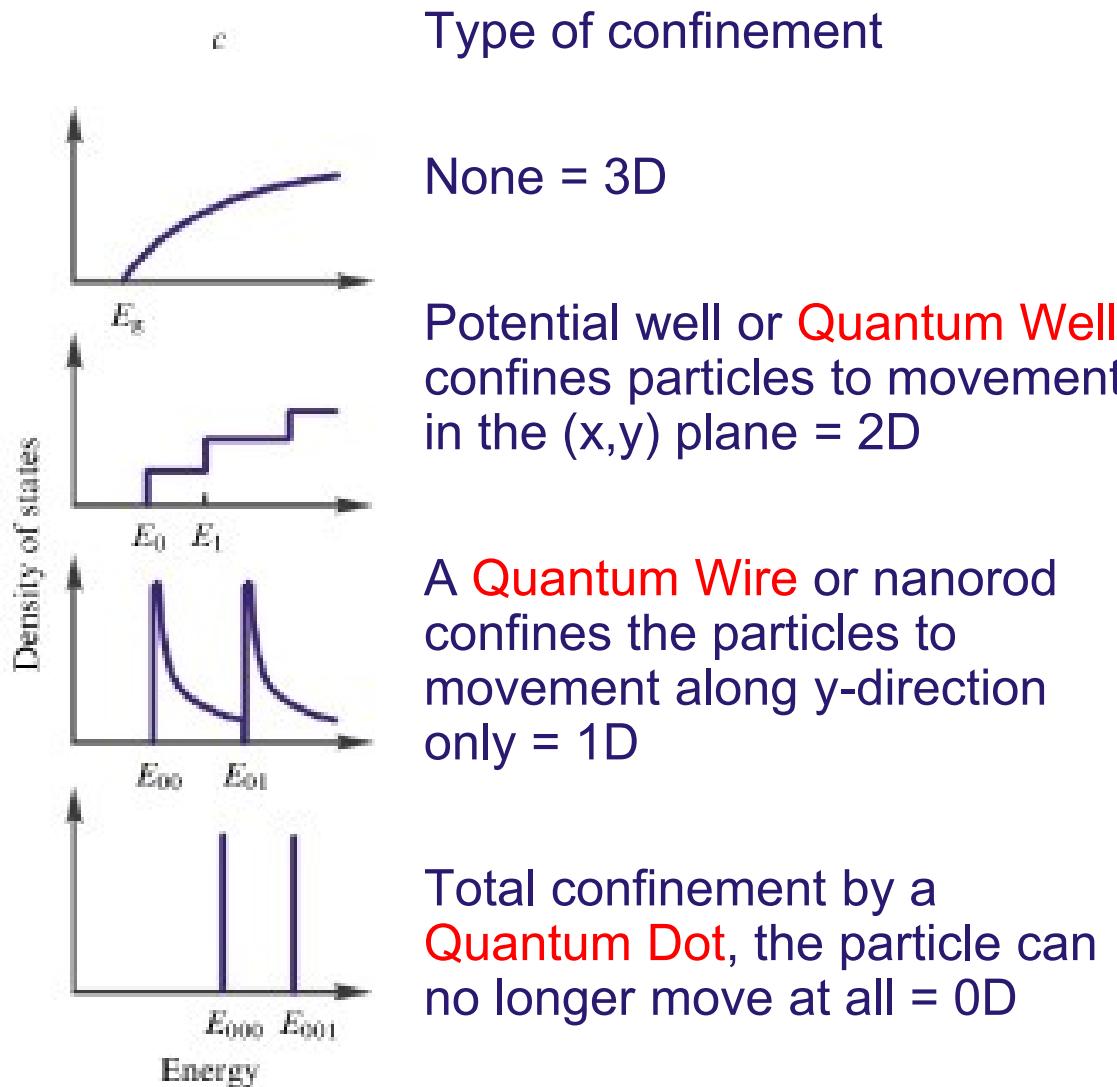
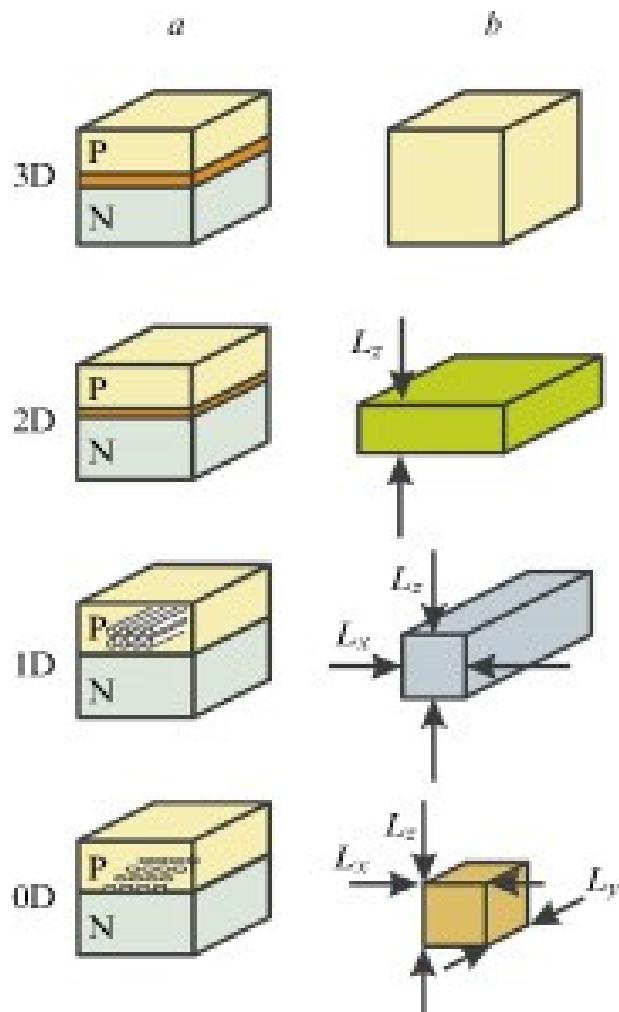


# Outline

- “How to?” – fabrication methods for nano-technology
- “What for?” – nano-technological devices
- “Where?” – typical application areas



# Motivation – DOS overview – 1

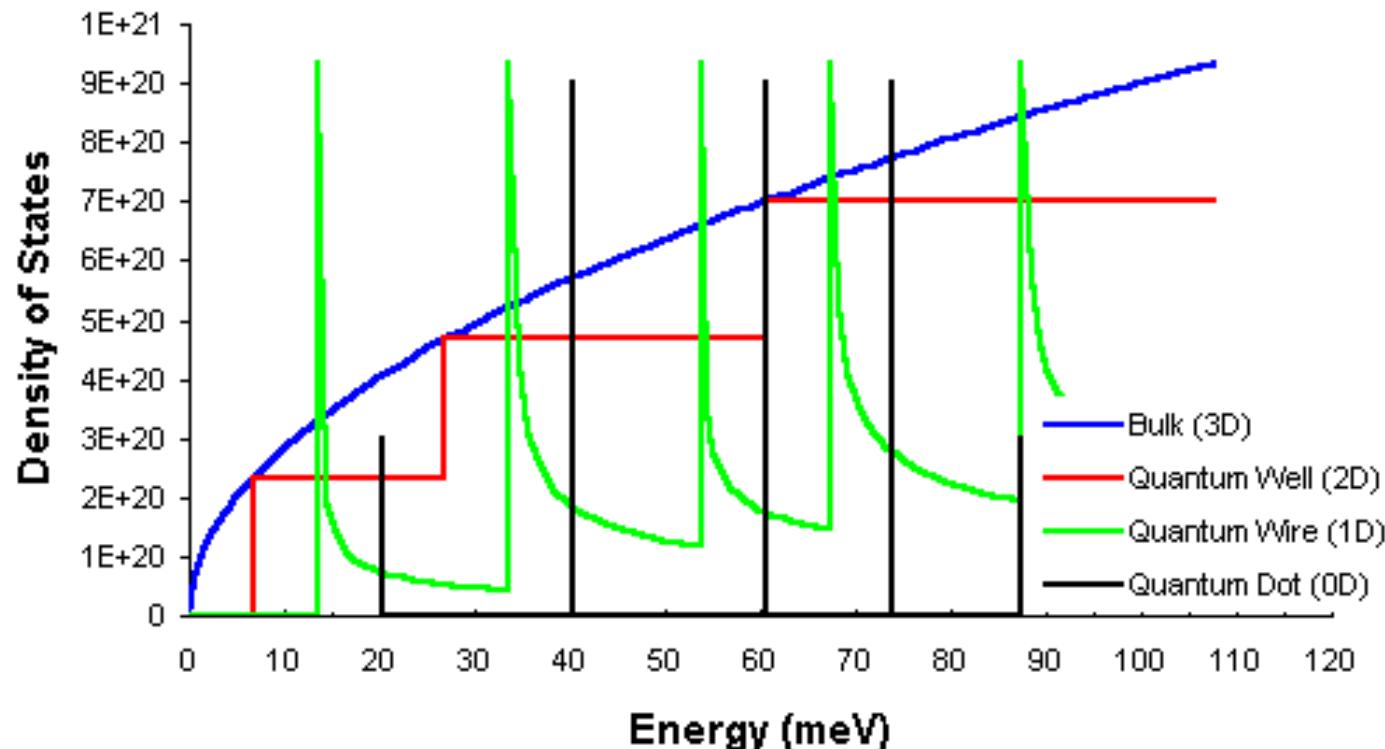




# DOS overview – 2

The stronger the confinement is, the more the initially continuous DOS splits up into discrete levels

This concentrates the density of states into an ever narrower a range of wavelengths in optical emission or absorption which is useful for optoelectronic devices





# Making the materials ...

## 1) Bulk

Growth of crystals, growth of “thick” layers on substrates

## 2) Quantum Wells

Formed using materials of different bandgaps (e.g. GaAs/AlGaAs)

Can also be formed by electrostatic gates and depletion/accumulation of bulk materials (MOSFETs) (3D → 2D)

## 3) Quantum Wires

Growth in ridges or grooves giving a local composition variation

Electrostatic gates to deplete a QW structure (2D → 1D)

Etching to create narrow channels

Self assembled nanowire growth

## 4) Quantum Dots

Self assembled growth using lattice mismatch (e.g. InAs/GaAs)

Electrostatic gates to deplete a QW structure (2D → 0D)

Inorganic synthesis routes – colloidal chemistry of nanocrystals



# Fabrication methods

## 1) Epitaxy

Growth of thin or thick layers

in-situ surface treatment (oxidation, nitridation, annealing)

## 2) Lithography

Enables localised deposition or etching

Metallisation for contacts, gates etc

## 3) Ion Implantation

Broad and selective area doping

Intermixing

## 4) Colloidal Chemistry

Formation of nano-rods or nano-crystals from suspensions

Surface functionalisation

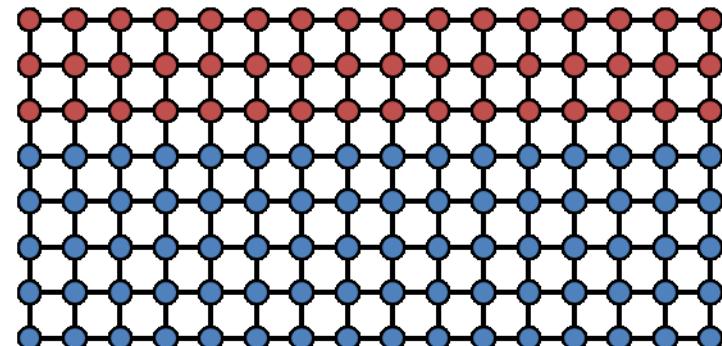
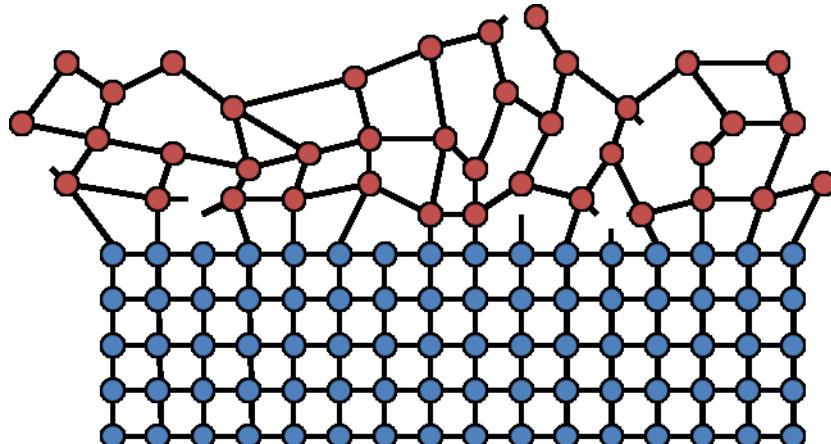


# 1) Epitaxy

The term *epitaxy* comes from the Greek roots *epi* (ἐπί), meaning "above", and *taxis* (τάξις), meaning "an ordered manner" → "arranging upon" (Wikipedia)

In short this means that the layer being grown has defined crystal orientation with respect to the substrate

This differentiates it from a simple “deposition” process

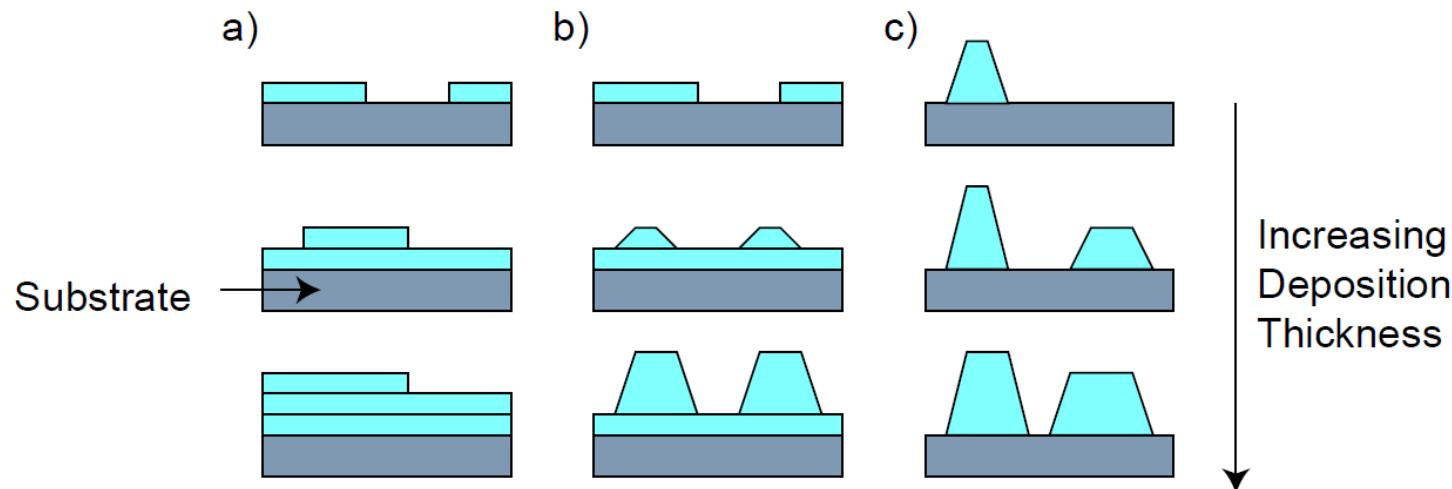




# Possible growth modes

Growth generally proceeds by one of three modes

Depends upon the interplay between lattice mismatch and surface energies and growth conditions (kinetics)



- a) Layer by Layer growth (Frank van der Merwe)
- b) Layer followed by Islanding (Stranski-Krastanov)
- c) Islanding (Volmer Weber)



# Some deposition techniques

## Liquid Phase Epitaxy (LPE)

Crystallisation of material onto a substrate from a molten solution

## Molecular Beam Epitaxy (MBE)

Crystallisation of material onto a substrate from one or more beams of evaporated elements/compounds

## Chemical Vapour Deposition (CVD)

Crystallisation of material onto a substrate from gas sources via a chemical reaction (e.g.  $\text{SiCl}_4 + 2\text{H}_2 \rightarrow \text{Si} + 4\text{HCl}$ )

## Metal-Organic Vapour Phase Epitaxy (MOVPE or MOCVD)

Crystallisation of material onto a substrate from gas sources via chemical reactions where one or more sources are Metal-Organics (e.g. TMAI -  $\text{Al}_2(\text{CH}_3)_6$ )

## Sputtering, Evaporation/Physical Vapour Deposition (PVD)

Do not necessarily create crystalline materials

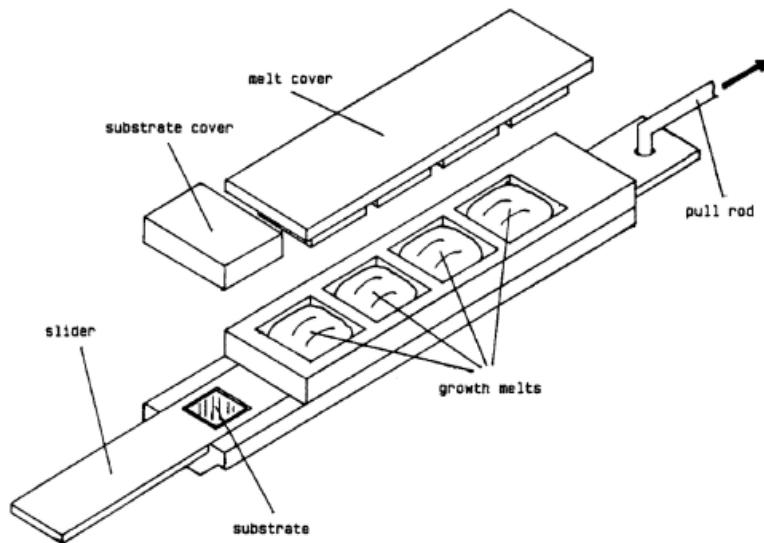


# Liquid Phase Epitaxy (LPE)

A substrate is brought into contact with a supersaturated melt of the material we wish to deposit and this crystallises on the surface

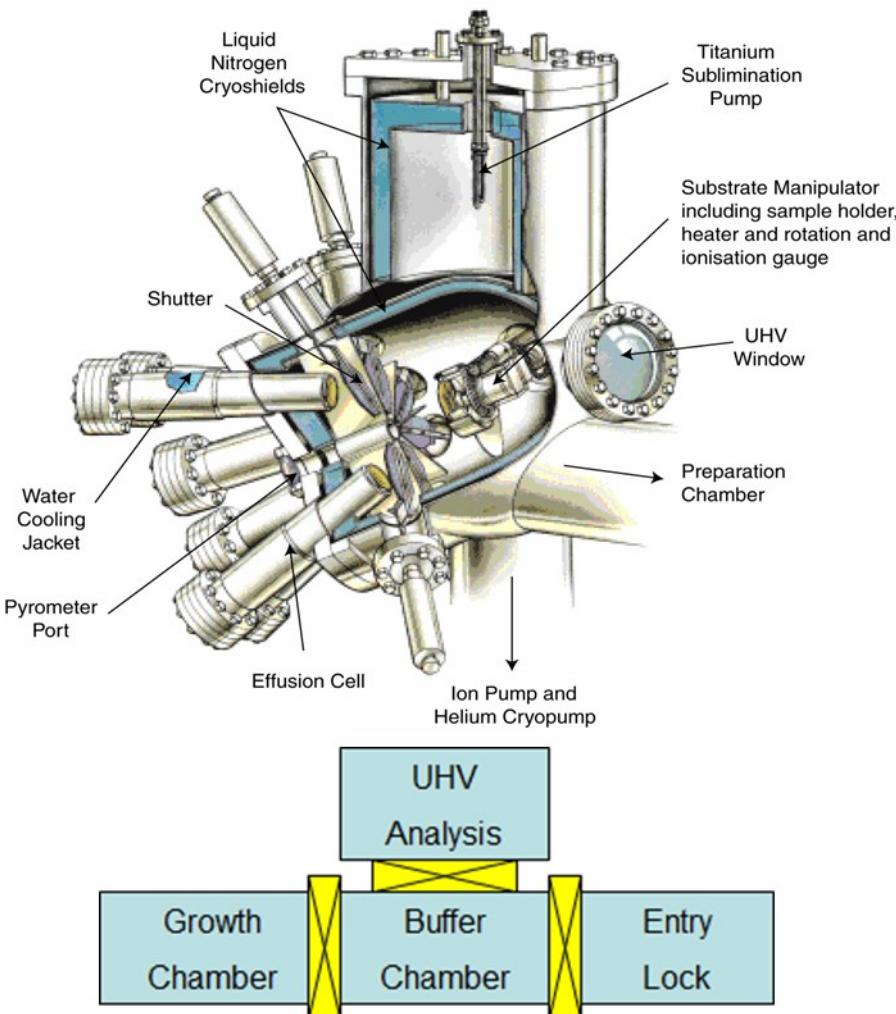
“Sliding boat” technology allows for heterostructure growth by bringing the substrate into contact with different melts at different stages of the growth

Interfaces are not particularly abrupt but growth rates are high making this a cheap and mass production method suitable for devices such as GaP LEDs





# Molecular Beam Epitaxy



Ultra High Vacuum deposition technique leading to low impurity levels

Chamber pressure  $10^{-11}$  mbar total

Partial pressure of impurities  $10^{-15}$  mbar

Beams of atoms or molecules produced from heated elemental/compound sources impinge on a heated crystalline substrate

Long mean free path between collisions meaning reactions take place on the substrate surface not in the gas phase (3m!!)

Abrupt interfaces possible due to relatively slow growth rate and fast acting mechanical shutters

Wide range of in-situ techniques for monitoring growth (RHEED, STM, AES, XPS etc.)

Applicable to a wide range of materials

Semiconductors – III-V, Si, Si-Ge, II-VI, IV-VI

Metals, Insulators, Organics (OLEDs)

Oxides ( $\text{ABO}_3$ , High Temperature Superconductors)



# Source Materials in III-V MBE

High purity source materials

99.99999% (7Ns) purity or higher

Group IIIs

Gallium, Aluminium, Indium

Group Vs

Arsenic, Phosphorous, Antimony,  
Nitrogen, Bismuth

Dopants

Beryllium (p), Magnesium (p)  
Silicon (n), Carbon(p), Tellurium (n)

Substrates

GaAs, InP, InAs, GaSb, InSb,  
Sapphire ... GaN, AlN, Ge, Si

Periodic Table of the Elements																	
1	H	IA	IIA	3	Li	4	Be	11	Na	12	Mg	19	K	20	Ca	21	Sc
2	2	He	0	5	B	6	C	7	N	8	O	13	Al	14	Si	15	P
3	11	Na	12	10	Ne	14	Si	15	P	16	S	17	Cl	18	Ar	35	Br
4	19	K	20	22	Ti	23	V	24	Cr	25	Mn	26	Fe	27	Co	28	Cu
5	37	Rb	38	39	Y	40	Zr	41	Nb	42	Tc	44	Ru	45	Rh	46	Pd
6	55	Cs	56	57	Hf	72	Ta	73	W	75	Re	76	Os	77	Ir	78	Pt
7	87	Fr	88	89	Rf	104	Ha	105	Sg	106	Ns	108	Hs	109	Mt	110	Au
*	Lanthanide Series	58	Ce	59	Pr	60	Nd	61	Pm	62	Sm	63	Eu	64	Gd	65	Tb
+	Actinide Series	90	Th	91	Pa	92	U	93	Np	94	Pu	95	Am	96	Cm	97	Bk





# Chemical Vapour Deposition

Generally takes place at a higher pressure than MBE leading to a much smaller mean free path ( $30\mu m$ )

A carrier gas ( $N_2$ ,  $H_2$ , He) transports the reactant species to the substrate, these may be gases, volatile liquids, sublimable solids or a combination of all

Molecules can interact and react in the gas phase

A wider variety of CVD reactions can take place

Pyrolysis, Reduction, Oxidation, Compound formation, Disproportionation, Reversible Transfer

e.g. reduction of silicon tetrachloride:  $SiCl_4 + 2H_2 \rightarrow Si + 4HCl$   
decomposition of silane:  $SiH_4 \rightarrow Si + 2H_2$   
n-doping by  $PH_3$  or  $AsH_3$ , p-doping by diborane ( $B_2H_6$ )  
(autodoping by impurities from substrate if growth is too slow!)

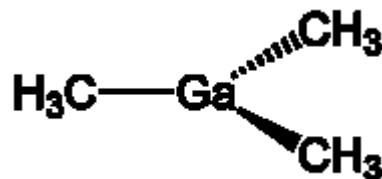


# Metal-Organic CVD (MOCVD)

Sometimes called Metal-Organic Vapour Phase Epitaxy (MOVPE)

Uses a mixture of gas sources and volatile metal-organics

TMGa = Trimethylgallium



e.g. Silane + Ammonia + TMGa → GaN:Si

Offers higher growth rates than MBE and is sometimes considered (incorrectly) as the only viable production technique

Used for a wide range of materials from InP based telecoms devices through GaN and CdTe

Potential issues with hazardous gas sources used



# In-situ surface treatment

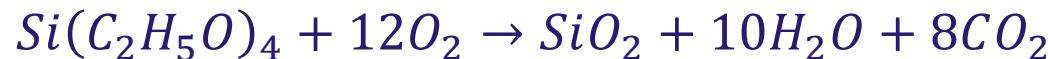
Dry Oxidation by molecular oxygen (slow)



Wet Oxidation under steam (fast)



Pyrolytic Oxidation of alkoxy silanes



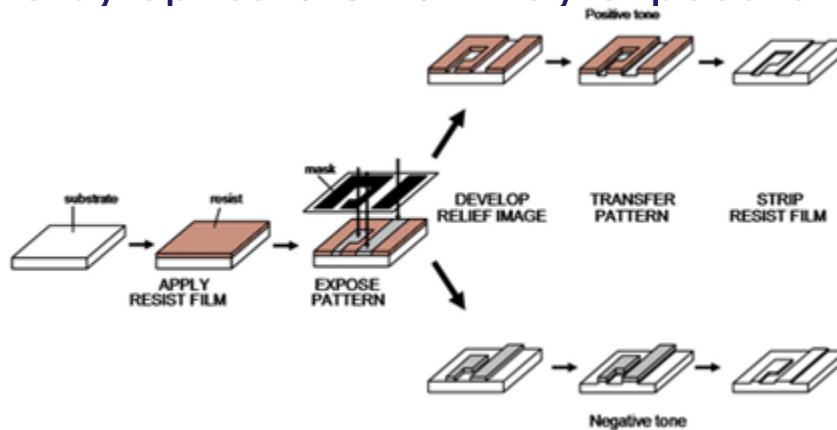
Nitridation with ammonia ( $NH_3$ ) forms  $Si_3N_4$  diffusion barriers

Rapid Thermal Annealing



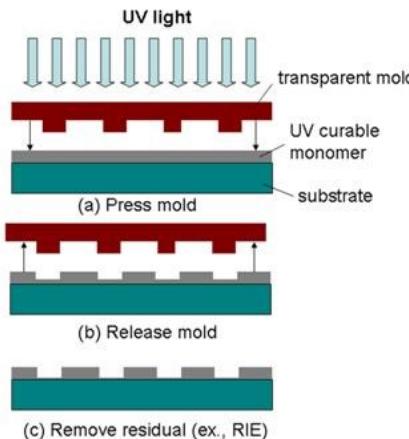
## 2) Lithography

Local patterning (deposition or etching) of structures on the surface **via masks** by optical / UV / X-ray exposure of resist



Focused ion or electron beam patterning (**direct writing**)

Nano-imprinting



- a. Prepare wafer
  - oxide
  - substrate
- b. Apply photoresist
  - PR
  - oxide
  - substrate
- c. Align photomask
  - glass
  - Cr
  - PR
  - oxide
  - substrate
- d. Expose to UV light
  - glass
  - Cr
  - PR
  - oxide
  - substrate
- e. Develop and remove photoresist exposed to UV light
  - PR
  - oxide
  - substrate
- f. Etch exposed oxide
  - PR
  - oxide
  - substrate
- g. Remove remaining photoresist
  - oxide
  - substrate



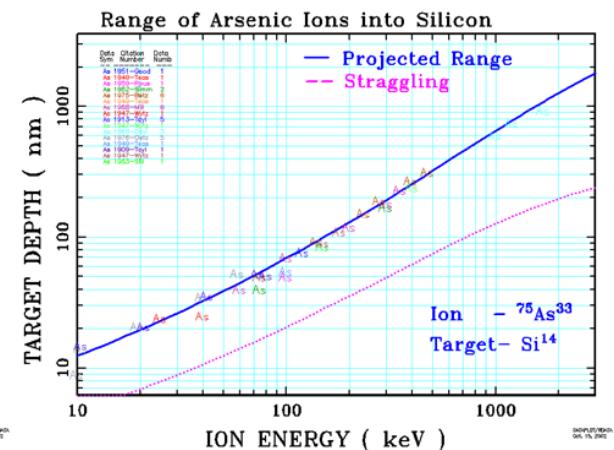
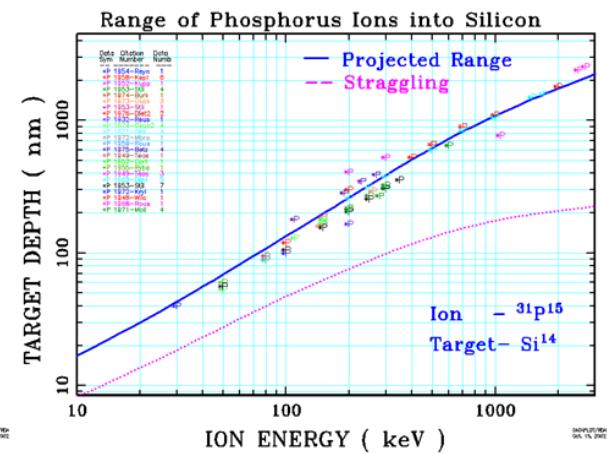
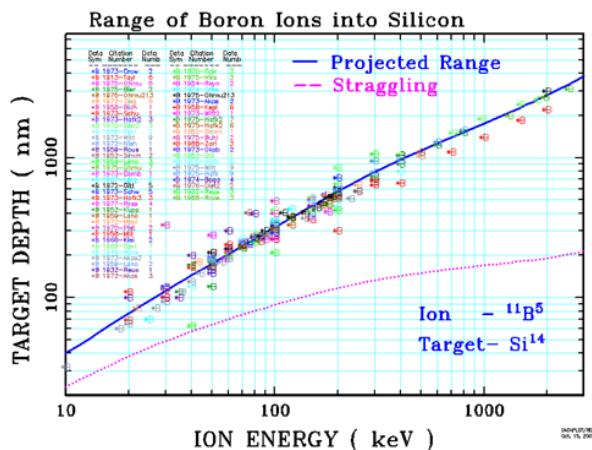
### 3) Ion Implantation

Implant high energy ions through a mask filter to a certain depth given by ion penetration range

Followed by annealing to bring interstitial atoms onto lattice sites (electrical activation)

“Straggling” is assumed to be the square root of the variance (data from J.F. Ziegler’s SRIM code)

Also can be used for intermixing (**disordering**) layers at a given depth by ion implantation





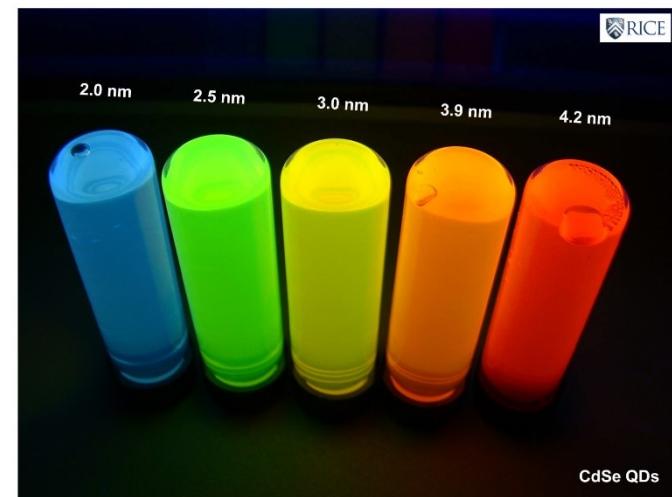
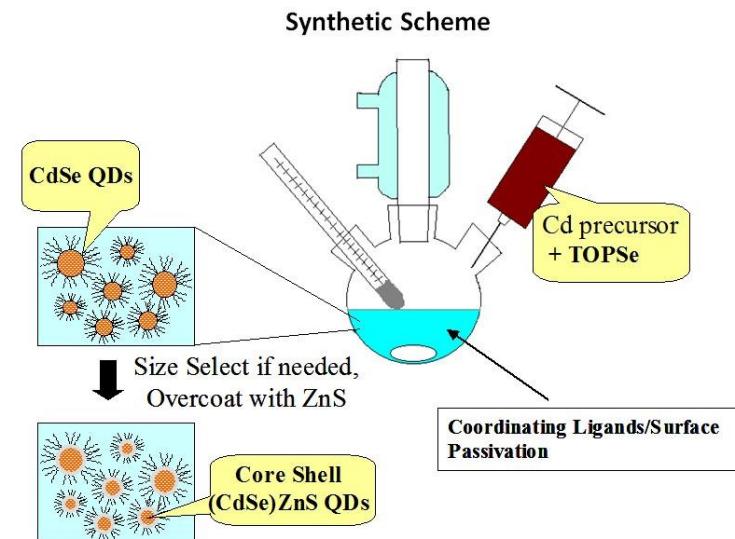
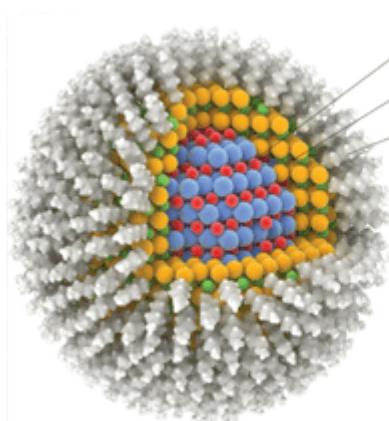
# 4) Colloidal Chemistry

Formation of nano-rods or nano-particles from crystallite growth in suspension

Size of nano-particles affects their properties, they are Quantum Dots...

Watch them being made at

<https://www.youtube.com/watch?v=bKLdkjV6Mbc>

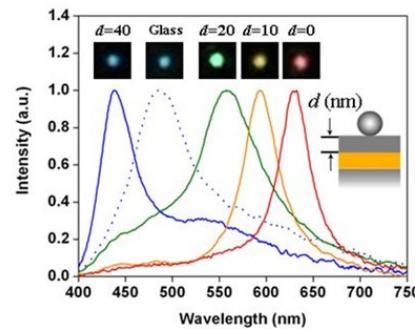
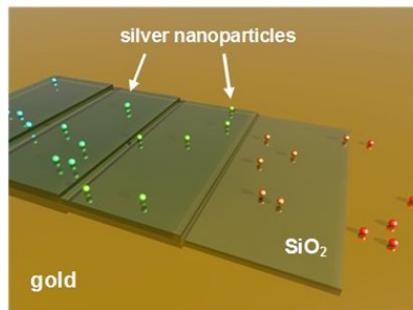




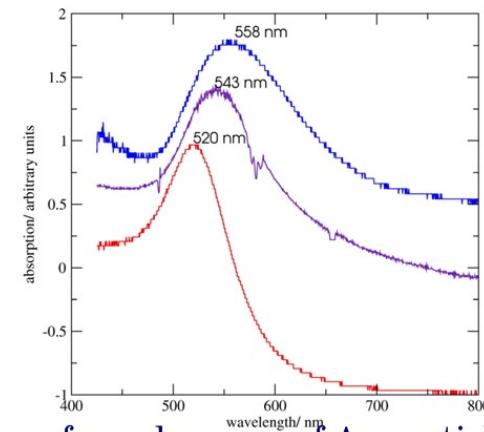
## 4) Colloidal Chemistry

Surface functionalisation by organic molecules to provide steric hinderance to clustering so that nano-particles remain separated

Dispersion of gold or silver nano-particles onto (patterned) semiconductor surfaces to improve light coupling via surface plasmons



surface plasmons of Ag particles as function of thickness of  $\text{SiO}_2$  interlayer to Au film



surface plasmons of Au particles as function of their diameters of 14 (red), 75 and 86 nm



# Nano-technological semiconductor devices

## 1) Electronics (voltage $\leftrightarrow$ current, charge storage)

Smaller and faster MOSFETs as switches and amplifiers

Devices for quantum computing based on single electrons or spins

## 2) Opto-Electronics (current $\rightarrow$ light)

More powerful LEDs

More powerful and longer lasting LASER diodes

Integration of LASERs with MOSFETs for optical computing (III-V on Silicon)

Quantum Cascade Lasers for tailored IR applications

## 3) Solar Cells (light $\rightarrow$ current)

New concepts incorporating quantum dot or quantum wire structures

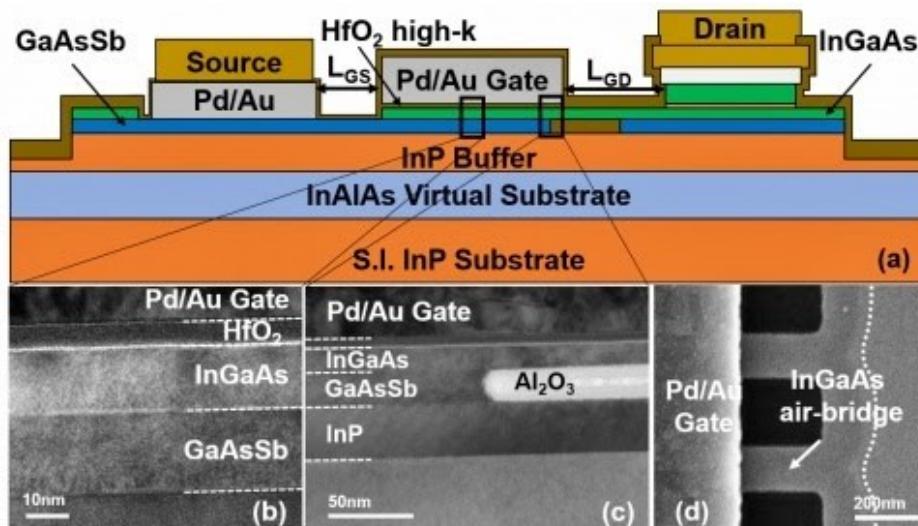
Improvement of surface coupling by plasmonics

Improved sub-wavelength anti-reflective coatings

Multi-junction solar cells

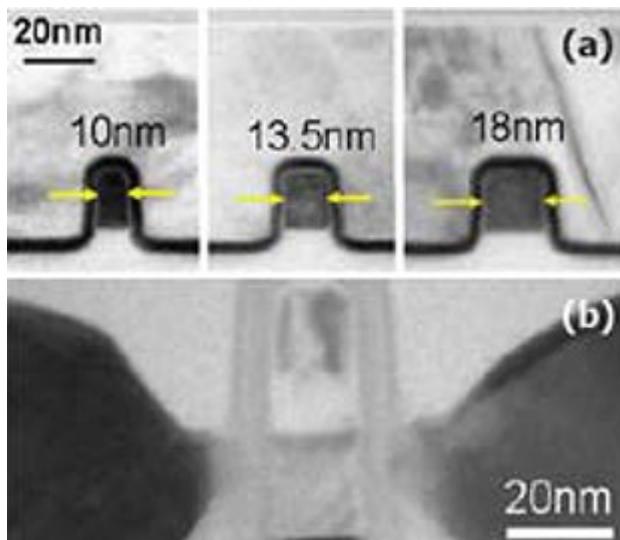


# MOSFETs: two recent highlights



Engineers from MIT are claiming to have fabricated the first tunnel FET with a double quantum well InGaAs/GaAsSb structure

Solar UK Conference, Watford (2014)



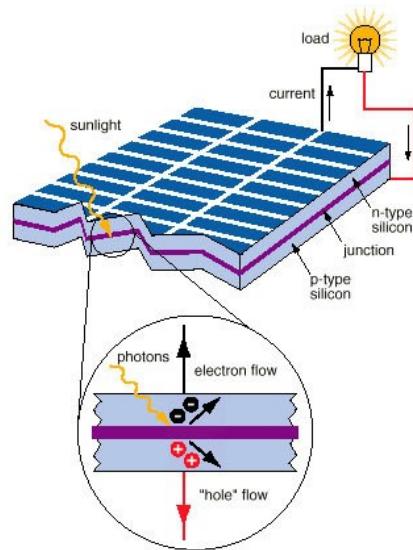
TEM cross-sectional images through probably the smallest MOSFET made by IBM and GlobalFoundries to date (2013!)

SiGe Tri-gate pFET with  
H=17nm, W=10-18nm, gate Length<20nm

(Hasemi et al, Symp. VLSI Technol. And Circuits, Tokyo (2013))



# Solar Cells: principles

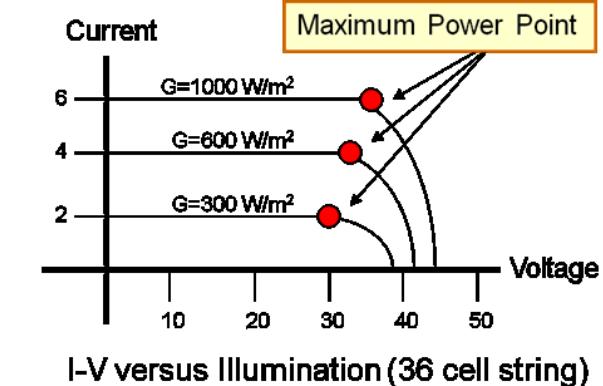
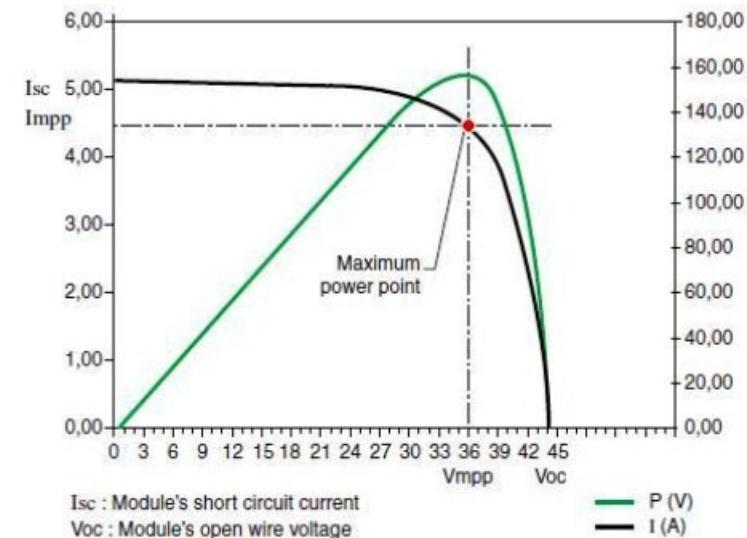


Principle: pn-junction as a solar cell

**Absorption of light**, generating electron-hole pairs

**Separation of charge carriers** by the built-in field ( $\sim 0.55V$  for a single Silicon cell)

**Extraction of charge carriers** to an external circuit, yielding a current that depends on load impedance



**power point tracking:** maximise the current  $\times$  voltage product



# Solar Cells: Efficiency

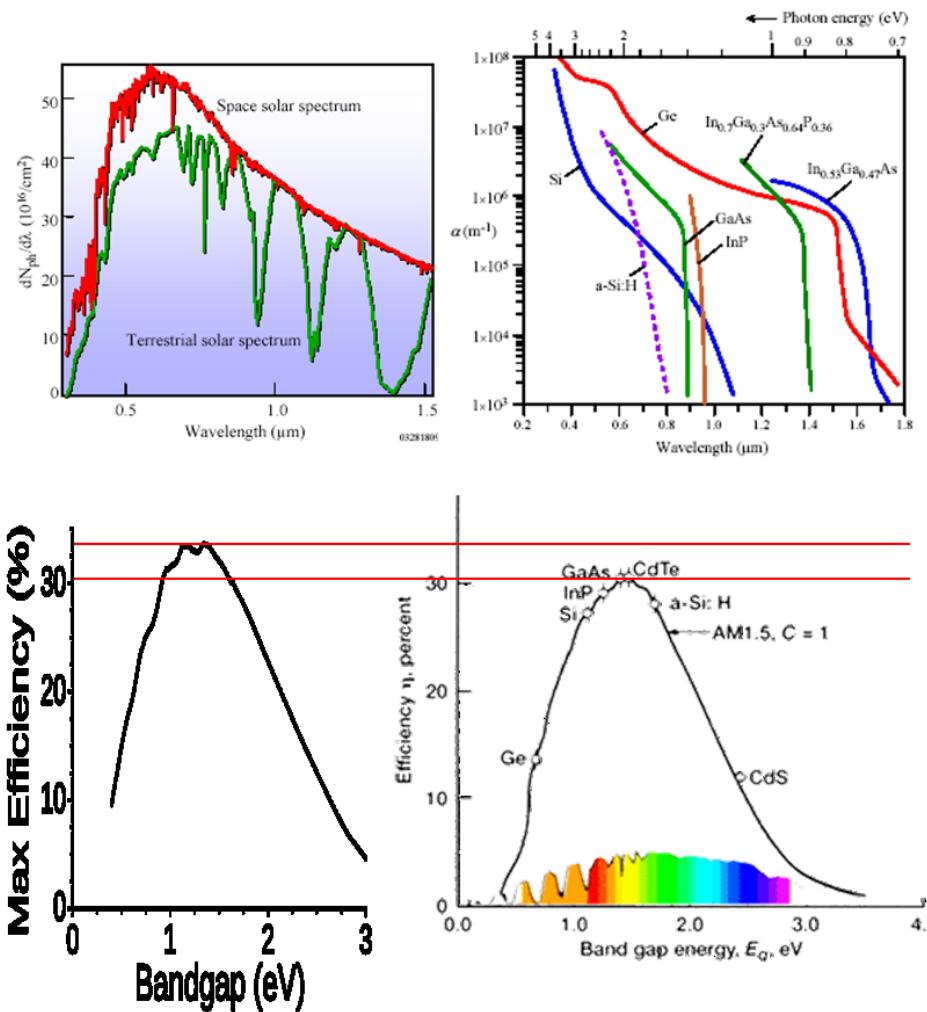
**Theoretical max. efficiency** of single-junction solar cells given by fraction of solar spectrum absorbed:

Only photons with the energy of the bandgap ( $E = E_g$ ) are converted with good efficiency.

Photons with lower energy are not absorbed at all.

Those with higher energy ( $E \geq E_g$ ) are reduced to band-gap energy by thermalization of the photogenerated carriers, so fraction  $\Delta E = E - E_g$  is wasted.

$$\eta^{\max} = 31 - 33\% \text{ for GaAs or CdTe}$$





# Solar Cells: Types

Main categories of photovoltaic cells

- 1) Crystalline Silicon (c-Si) solar cells
- 2) Thin Film Solar Cells (TFSC)
- 3) Multi-junction Solar Cells (MTJ)

category	technology	$\eta$ (%)	$V_{oc}$ (V)	$I_{sc}$ (A)	W/m <sup>2</sup>	$t$ ( $\mu$ m)
c-Si	mono-cryst.	24.7	0.5	0.8	63	100
	poly-cryst.	20.3	0.615	8.35	~200	200
TFSC	amorphous Si	11.1	6.3	0.0089	33	1
	CdTe	16.5	0.86	0.029	~100	5
	$CuIn_xGa_{(1-x)}Se_2$ (CIGS)	19.5	—	—	—	1
multi-junction cells	III/V's on Ge	40.7	2.6	1.81	476	140



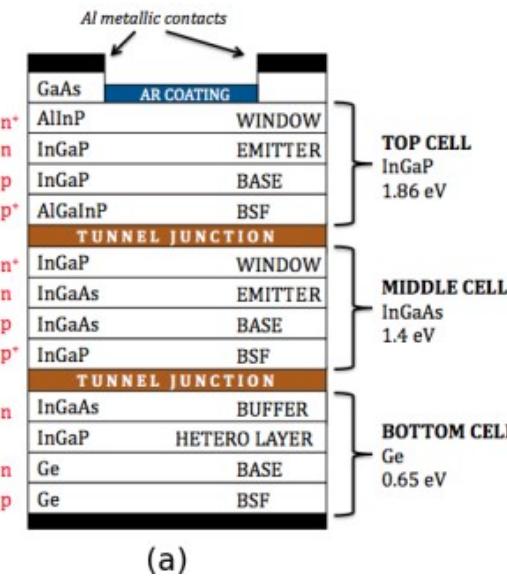
# Solar Cells: Thin Film Solar Cells



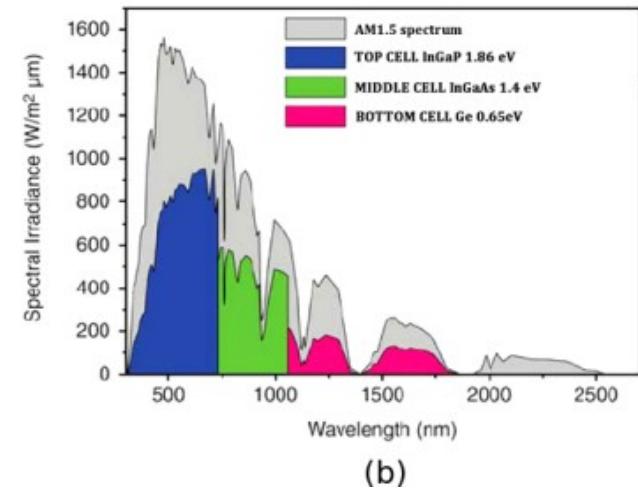
**Desert Sunlight, CA, USA:** the largest solar photovoltaic installation in the world (as of March 2015): 8 million **thin-film CdTe based** solar cells on 3800 acres , 550MW, powering 160 000 average homes



# Solar Cells: Multi-Junction



(a)

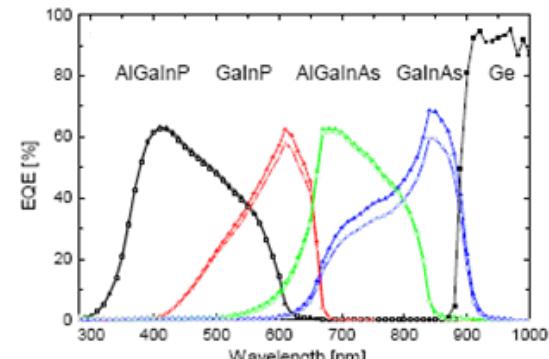
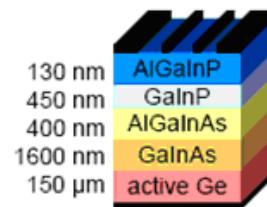


(b)

**GaAs based** triple junction solar cells,  
10kW, powering NASA satellite DAWN,  
launched Sep. 2007

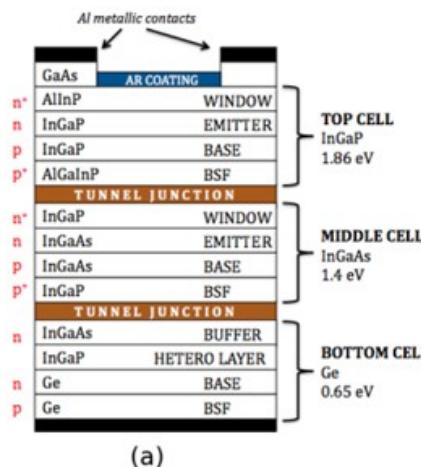
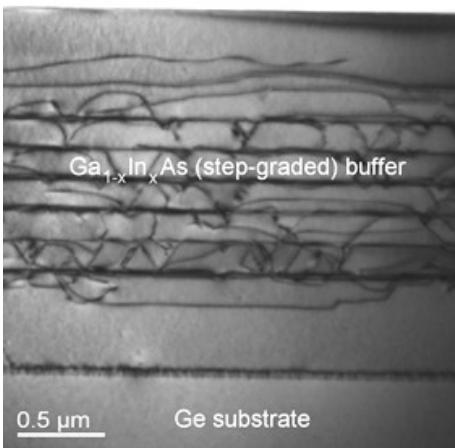
**idea: lowest band-gap material at bottom**, because IR has larger penetration depth!  
max. efficiency at high cost!

above: layout of triple junction solar cell for  $\eta^{\max} \approx 50\%$  (from U Strathclyde)  
below: layout of 5-layer solar cell (from AW Bett, Proc. Solar Power Conf. 2006)





# Solar Cells: Multi-Junction



## Search for new (lattice matched) candidate materials

The addition of small amounts of Nitrogen or Bismuth to GaAs dramatically changes the band structure

GaAsBiN could provide a 1.0eV material lattice matched to GaAs or Ge

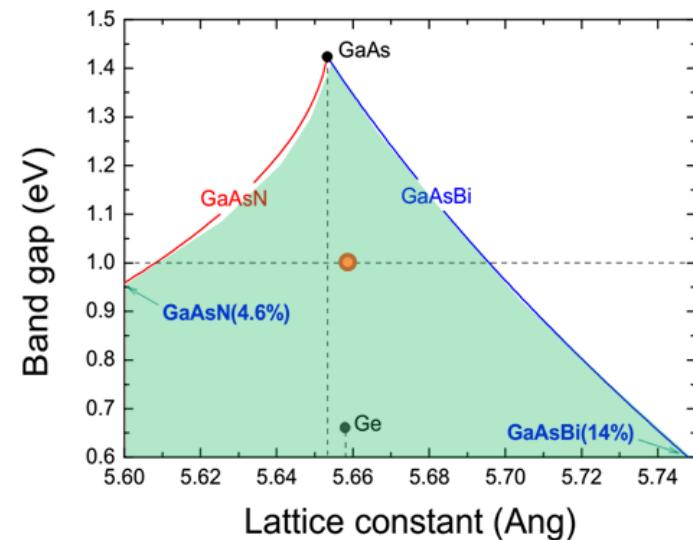
Offers the potential for an InGaP/GaAs/GaAsBiN/Ge 4-junction solar cell with no strained layers

## Materials challenges to solve:

Lattice mismatched materials give rise to dislocation formation at the interfaces

Need graded regions and dislocation filters which is more complex and means thicker devices

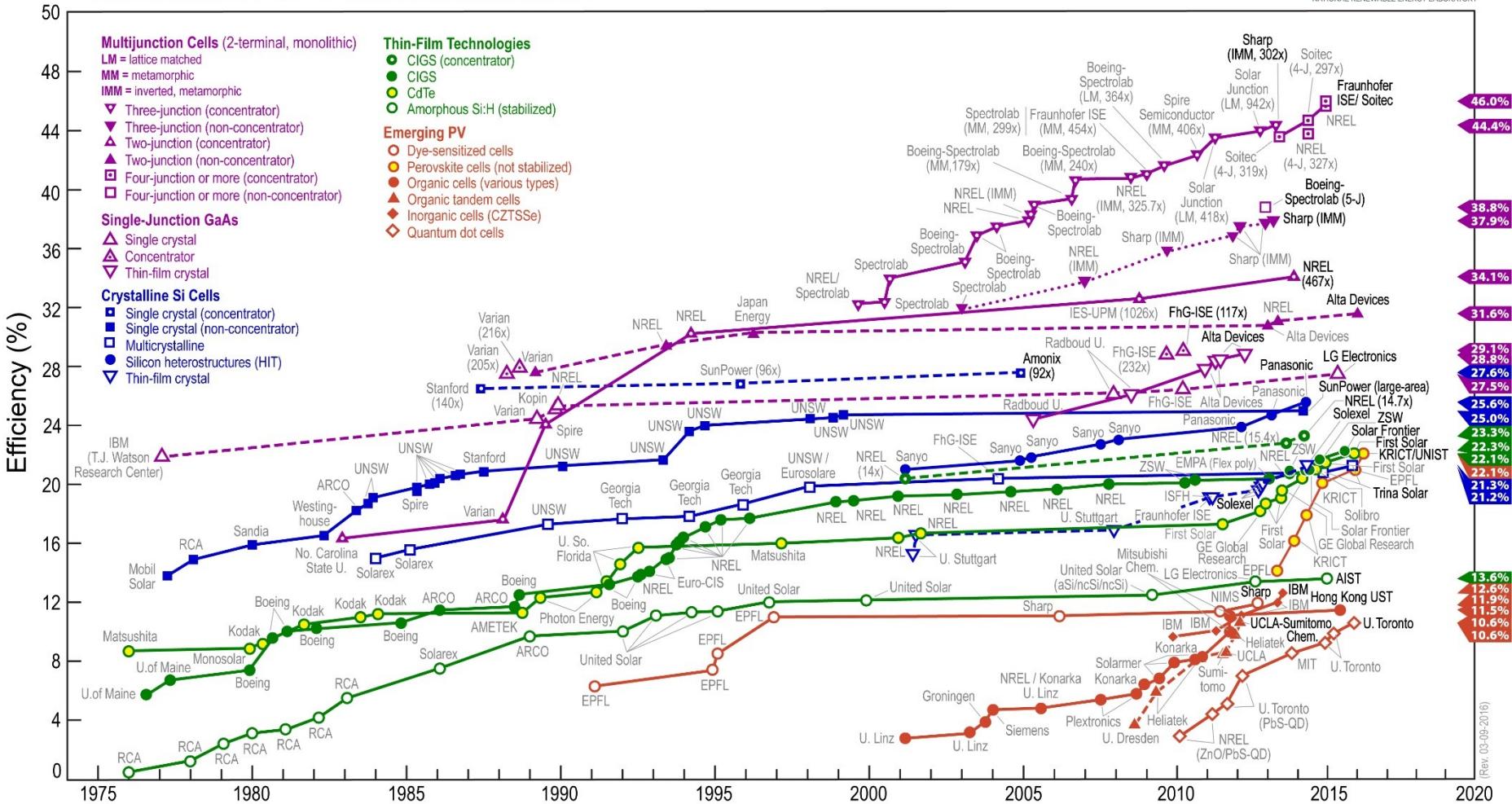
Reuse of expensive substrates to reduce total cost of cell fabrication



Sweeney, S.J., K. Hild, and J. Shirong. 2013 IEEE 39th. 2013.

# Solar Cells: Comparison of Types

## Best Research-Cell Efficiencies





# Nano-technological applications

## 1. physics

- a. improved data storage
- b. quantum computing schemes

## 2. chemistry

- a. more efficient catalysts
- b. water and dirt-repellent surfaces ('lotus effect')

## 3. medicine

- a. colour coded quantum dots for in-vivo imaging of living organisms in 3D
- b. colour coded quantum dots for DNA testing
- c. improved healthcare and cancer treatments by quantum dot assisted drug delivery

## 4. other

- a. invisible watermarking of goods and banknotes
- b. forensics, e.g. nano-particles in gunshot residue

This list is by no means exhaustive!!